



Local Oscillators and Mass Sensors for IMPACT

Eun Sok Kim

Department of Electrical Engineering-Electrophysics
Viterbi School of Engineering
University of Southern California
E-mail: eskim@usc.edu

The views, opinions, and/or findings contained in this presentation are those of the presenter and should not be interpreted as representing the official views, either expressed or implied, of the Defense Advanced Research Projects Agency or the Department of Defense.

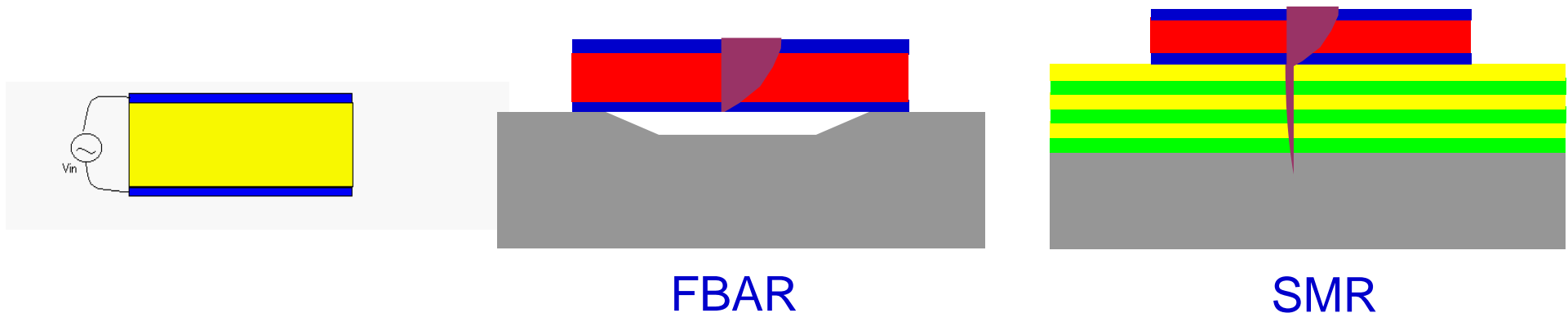
May 15, 2008

Approved for Public Release, Distribution Unlimited

Film Bulk Acoustic Resonator (FBAR)

□ Film bulk acoustic resonator (FBAR).

↪ Large acoustic impedance mismatch on both sides of piezoelectric film.



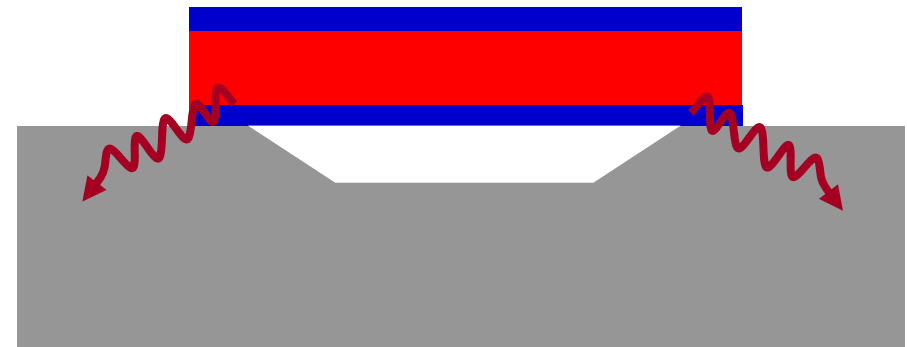
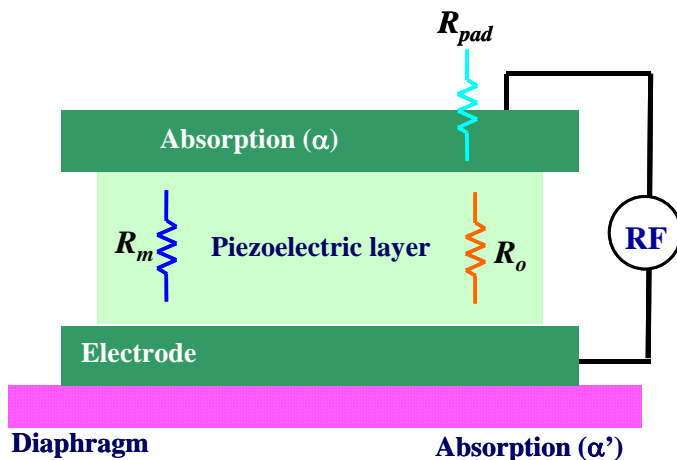
➤ <i>Impedance mismatch:</i>	Air	Bragg reflector (<u>frequency dependent</u>)
➤ <i>Energy confinement:</i>	Excellent	Shear wave propagates into substrate
➤ <i>Power handling:</i>	Good	Better (thermal flux through substrate)
➤ <i>Manufacturing:</i>	More masks	Multi-layers(>7): thickness control

Improving Q factor of FBAR

$$Q \equiv \frac{\omega \cdot (\text{Stored energy})}{\text{Dissipated energy (per cycle)}}$$

➤ Acoustic energy loss.

- thickness excitation
- in-plane lateral modes



➤ Minimize lateral acoustic loss (lamb wave) through the supporting areas.

➔ Free standing structure

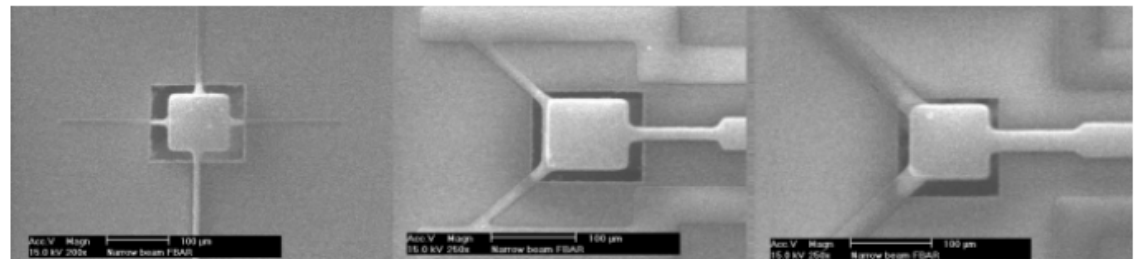
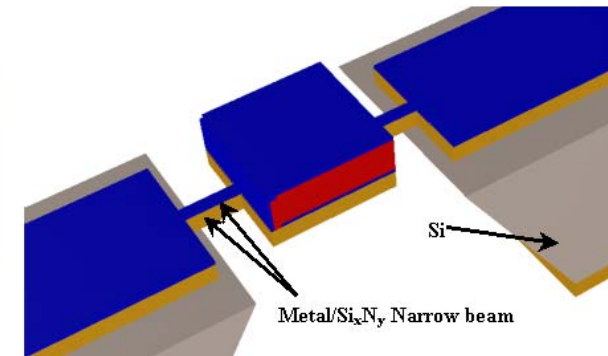
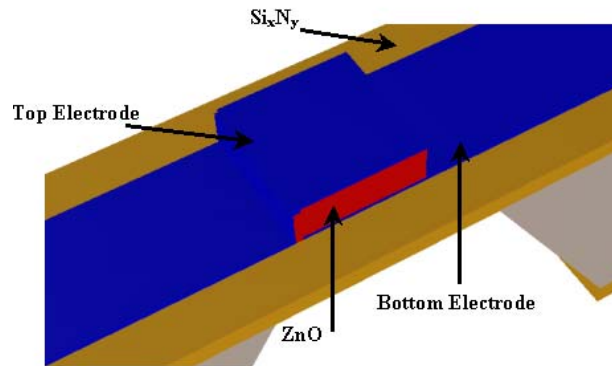
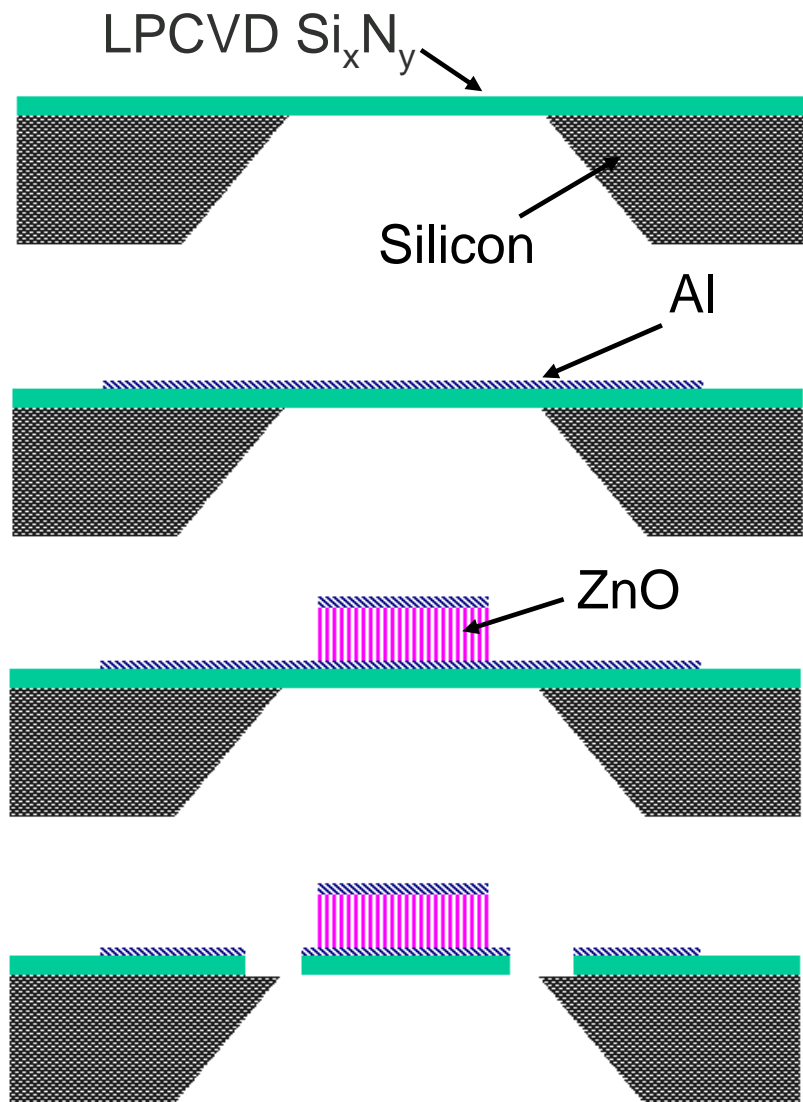
➤ Dielectric loss: Q_p (ZnO vs. AlN)

➤ Ohmic loss (R_s) : Q_s

➤ Improve crystalline quality of piezoelectric film

➤ Polish surface of ZnO or AlN.

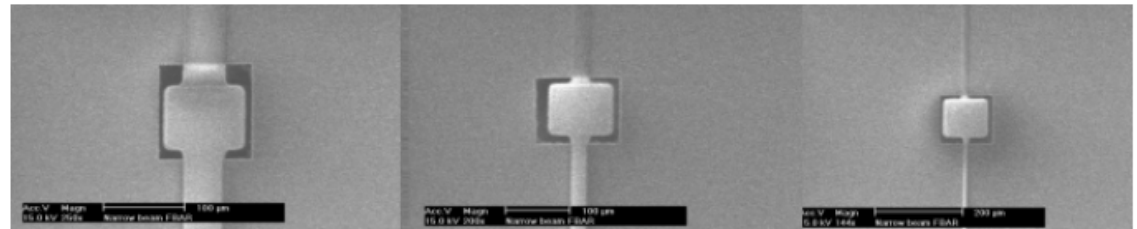
Narrow Beam Supported FBARs on Silicon



(a)

(b)

(c)

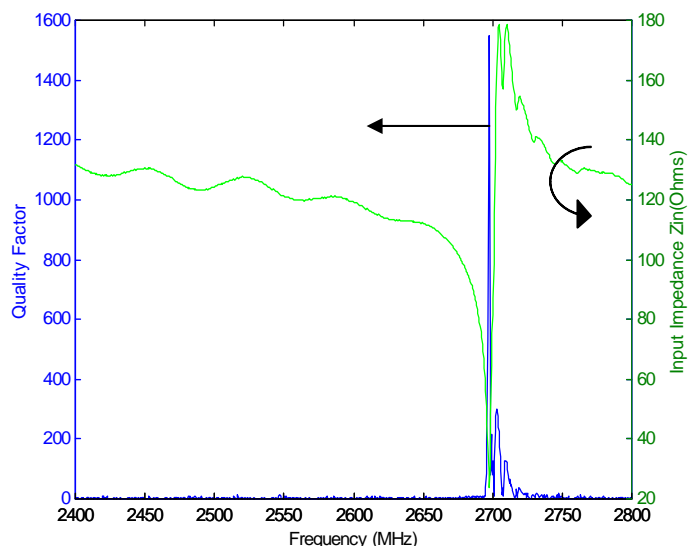


(d)

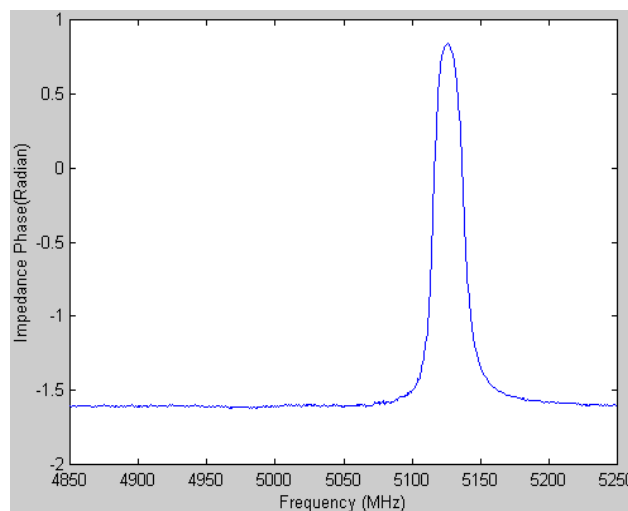
(e)

(f)

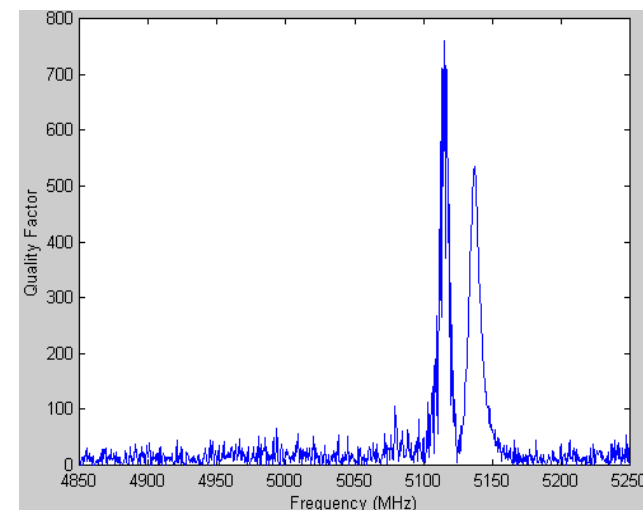
Experimental Results of Narrow Beam Supported FBARs at 2 and 5GHz



FBAR at 2GHz



Phase of FBAR impedance vs. frequency.



FBAR Q vs frequency.

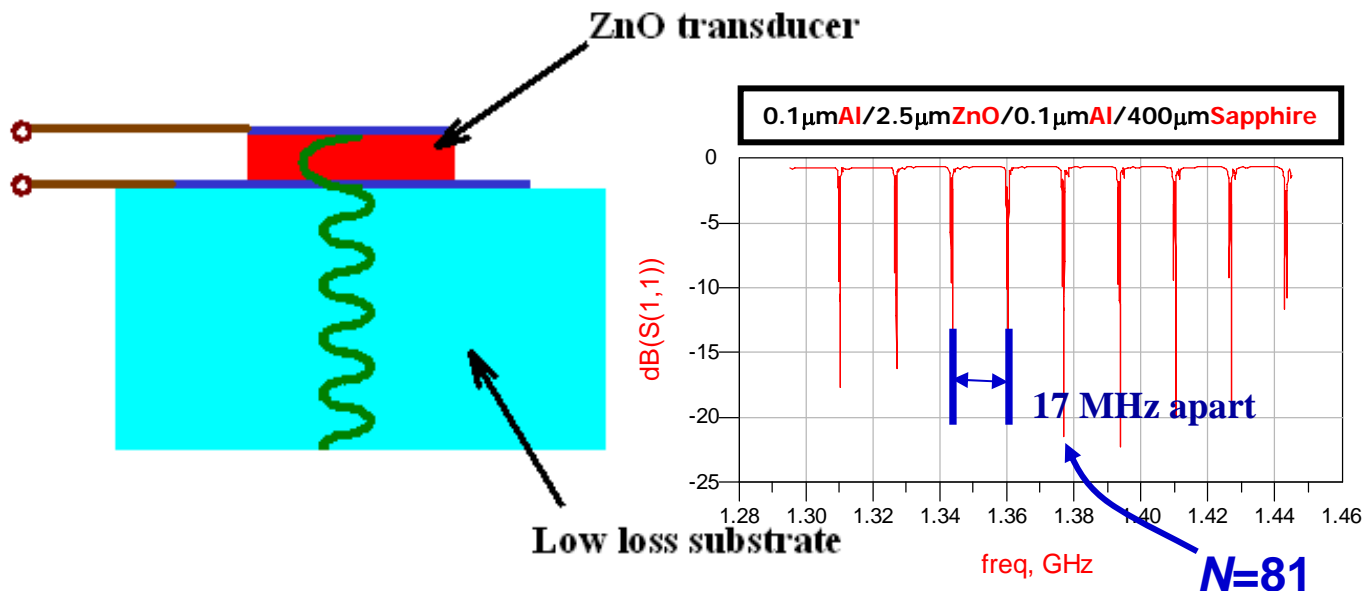
ZnO active area size ($\mu\text{m} \times \mu\text{m}$)	100 x 100					
Beam width (μm)	10		25		50	
Number of beams	2	4	2	3	2	3
Q factor@ 5.1GHz excluding electrode series and contact resistances	769	649	605	580	525	517

- ❑ Free-standing, isolated FBAR
 - Higher Q with
 - narrower support beam
 - less number of support beams

Bulk Acoustic Resonators

□ Film bulk acoustic resonator (FBAR).

↪ Large acoustic impedance mismatch on both sides of piezoelectric film



$$f_r \approx \frac{N}{2(d_{\text{ZnO}}/V_{\text{ZnO}} + d_{\text{substrate}}/V_{\text{substrate}})^{-1}}$$

Highest f·Q Region

Fundamental mode : ~17MHz

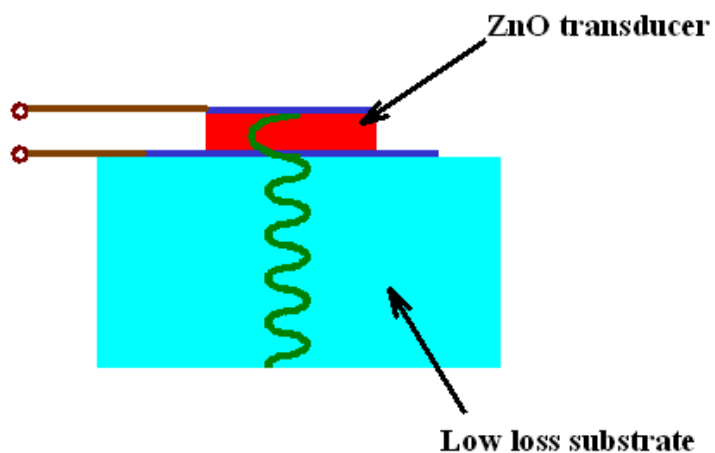
$V_{\text{sapphire}} \approx 11,100\text{m/s}$, $d_{\text{sapphire}} \approx 400\mu\text{m}$

□ High-tone bulk acoustic resonator (HBAR).

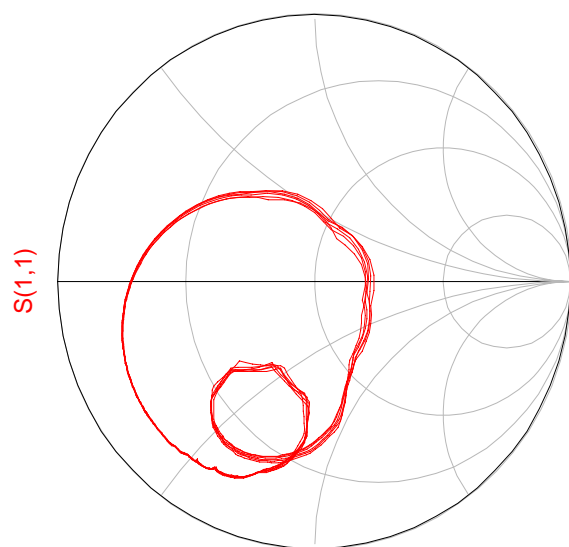
↪ Multiple resonances at an interval of tens of MHz.

↪ Extremely high Q with a low loss and double-side polished (~10Å) substrate.

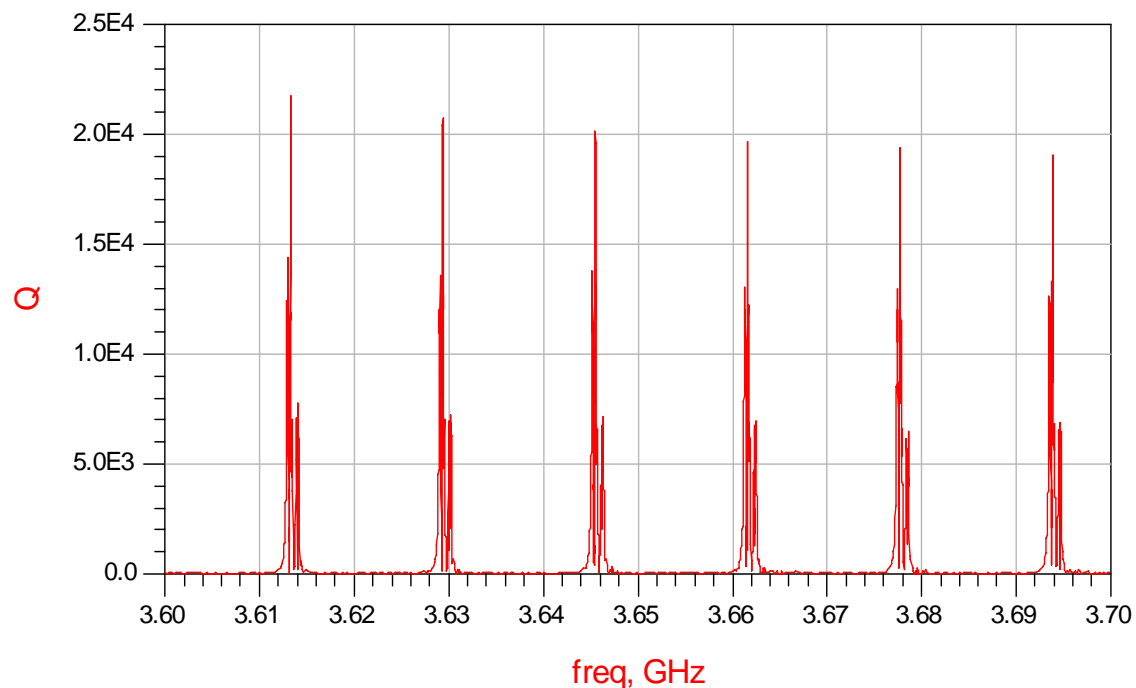
Measured 3.6 GHz HBAR Characteristics



0.1 μm Al/1.0 μm ZnO/0.1 μm Al/400 μm Sapphire

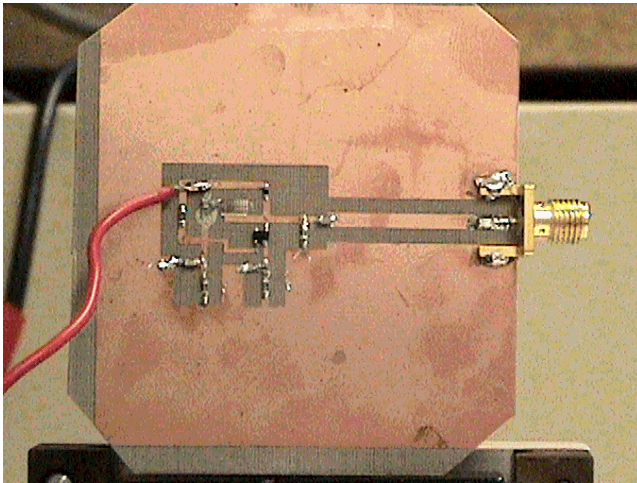


freq (3.600GHz to 3.700GHz)

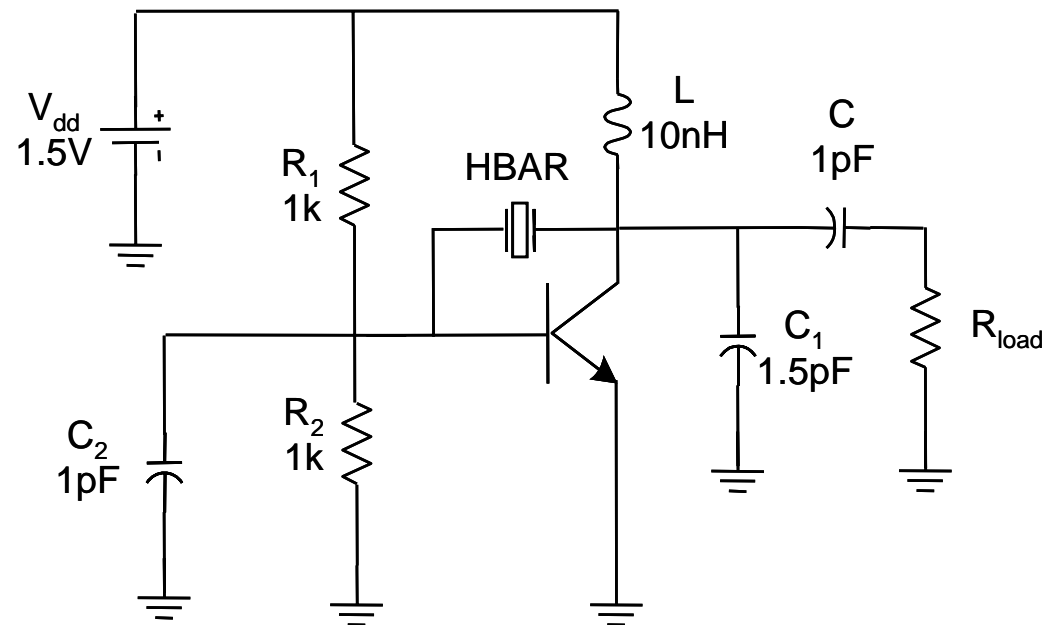
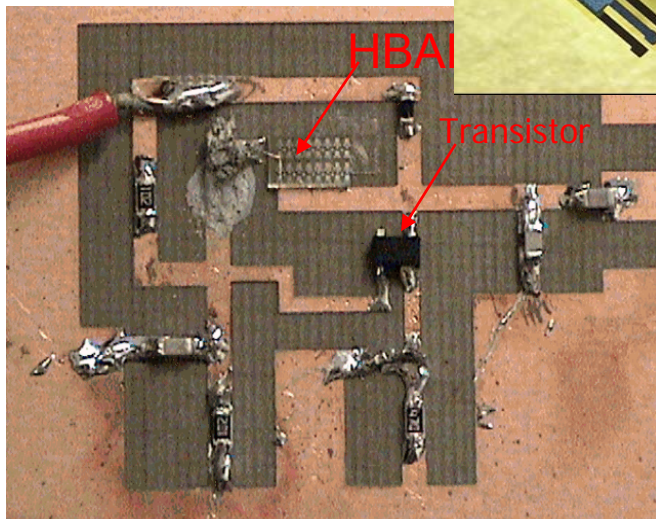


Q is around 19,000 at 3.677GHz

HBAR-Based 3.6 GHz Oscillator on PCB



HBAR's $Q = 19,000$ at 3.6 GHz



- ❑ Wire bonding on HBAR; epoxy used for one-side connection to PCB due to small area reserved on PCB.
- ❑ PCB not good looking due to many trials and errors (bypassing and replacing) during this first phase of the oscillator building.

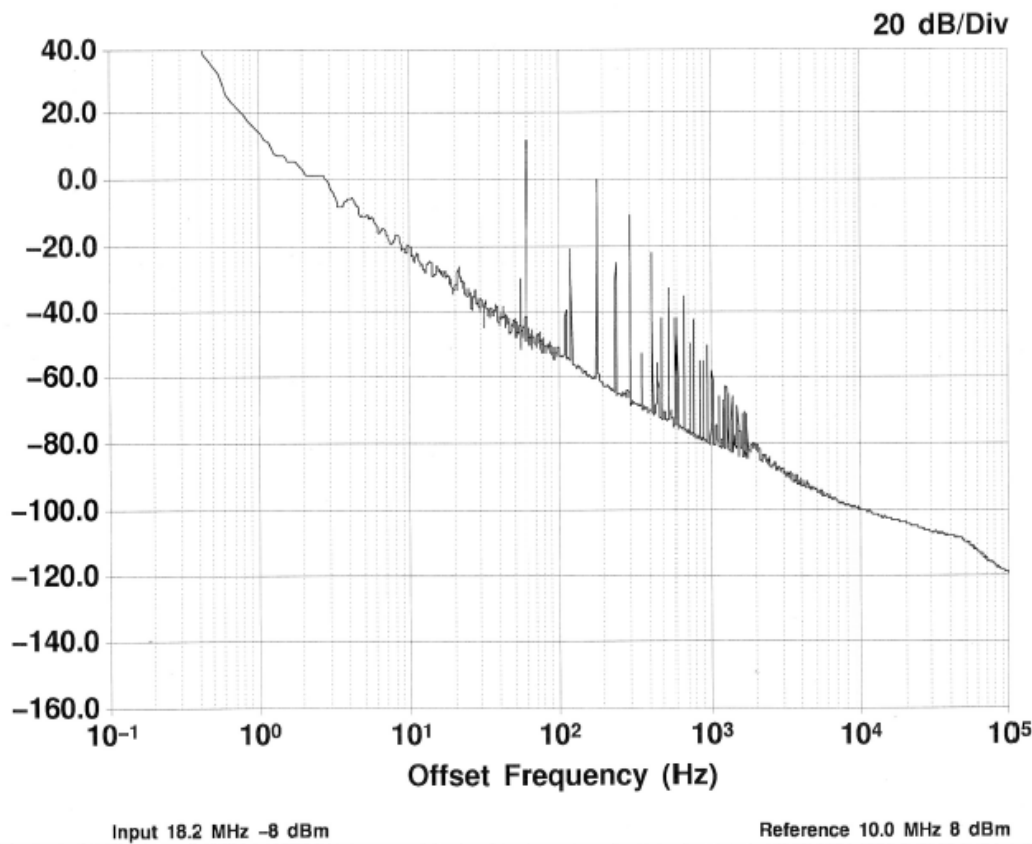
Phase Noise of 3.6 GHz HBAR-Based Oscillator

□ Alan Brannon of J. Kitching's Group at NIST measured the phase noise on a Timing Solutions TSC 5120A phase noise test set.

08 May 2006 18:27:46
Om

SSB Phase Noise at 18.2 MHz (dBc/Hz)

TSC 5120A



❖ Signal was down-converted to the required range of frequencies between 1MHz and 30MHz.

❖ Reference frequency was a frequency from a synthesizer that was externally referenced to a hydrogen maser ensemble.

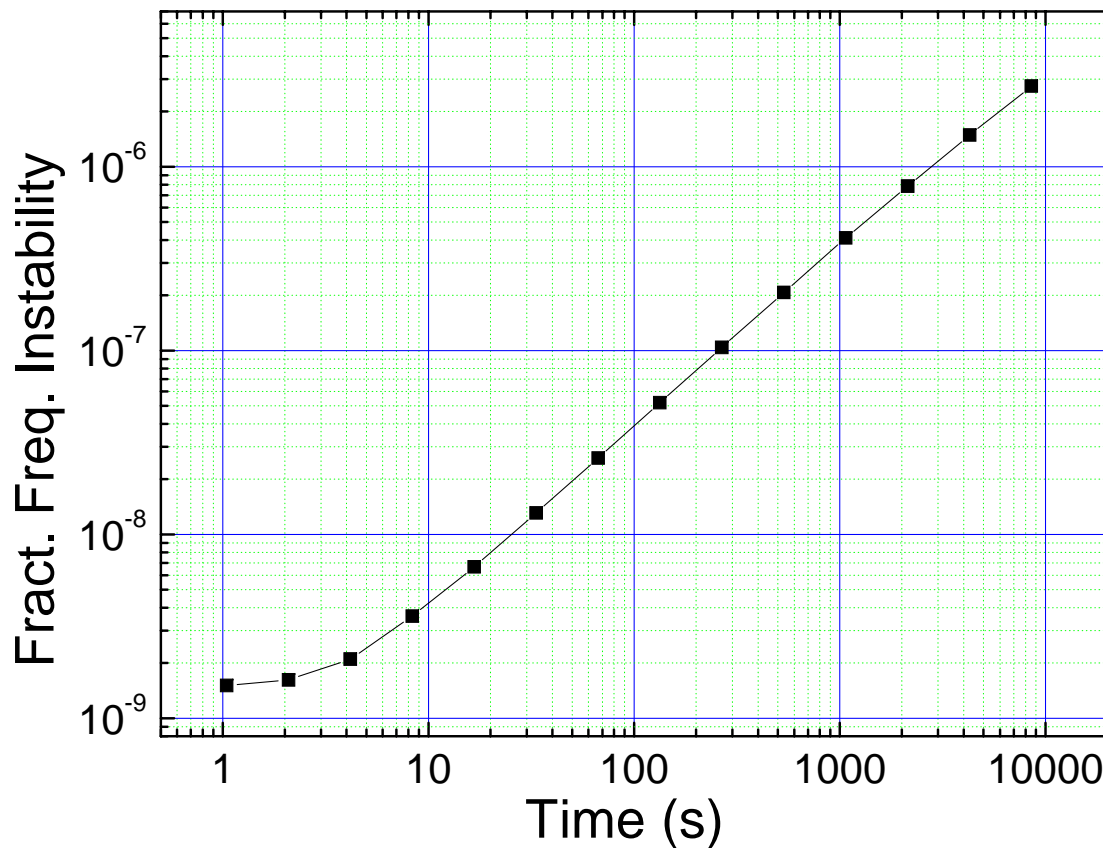
❖ Additive mixer noise was low enough to make these measurements.

Phase noise: -102dBc/Hz at 10kHz offset

Power consumption: 3.2mW

Measured Allan Deviation of HBAR-Based Pierce Oscillator

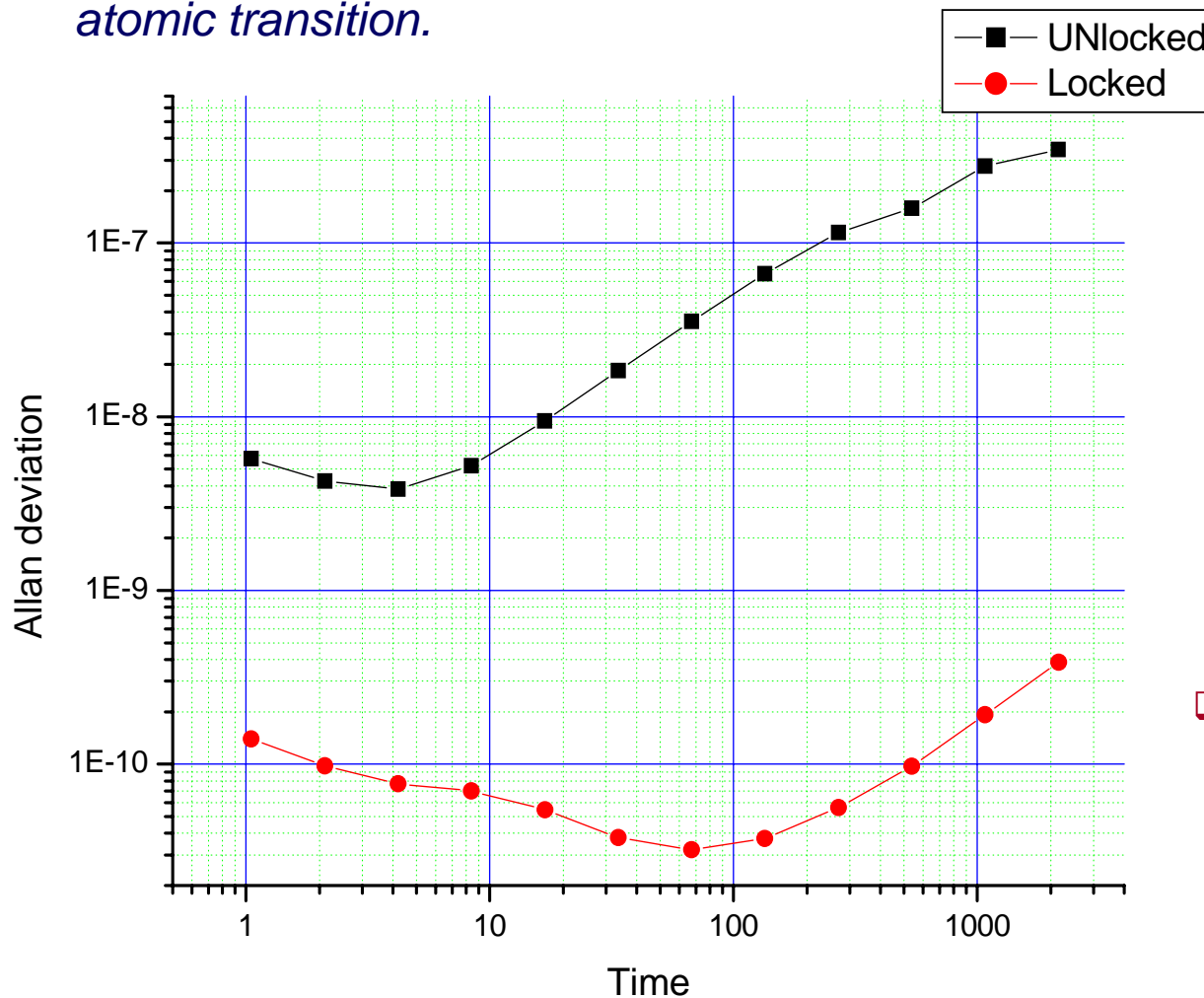
□ Alan Brannon of J. Kitching's Group at NIST measured the Allan deviation.



<i>Time(s)</i>	<i>Allan deviation</i>
1.04	1.5×10^{-9}
2.08	1.6×10^{-9}
4.17	2.1×10^{-9}
8.35	3.6×10^{-9}
16.7	6.7×10^{-9}
33.4	1.3×10^{-8}
66.8	2.6×10^{-8}
133	5.2×10^{-8}
267	1.0×10^{-7}
534	2.1×10^{-7}
1068	4.1×10^{-7}
2137	7.9×10^{-7}

Measured Allan Deviations

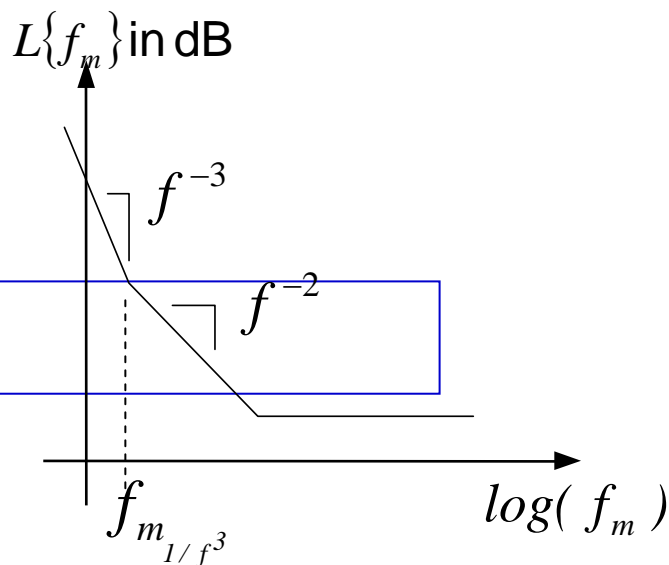
- ❑ The HBAR oscillator was locked up to NIST's table-top CPT physics assembly
 - by mixing it with a 200 MHz signal from a synthesizer to get the frequency near the atomic transition.



- ❑ Locked Allan deviation is 1.5×10^{-10} @ 1 sec

Modified Leeson's Equation for Phase Noise

$$L\{f_m\} = 10 \log \left[\left\{ 1 + \frac{f_o^2}{(2f_m Q_{load})^2} \right\} \left\{ 1 + \frac{f_c}{f_m} \right\} \frac{F k_B T}{2P_{s,av}} + \frac{2k_B T R K_o^2}{f_m^2} \right]$$



f_m : frequency offset from the center frequency

f_o : center frequency

f_c : flicker frequency

Q_{load} : loaded Q of the tuned circuit

F : noise factor (linear value for noise figure in dB scale)

$k_B T$: 4.1×10^{-21} at 300K

$P_{s,av}$: average power at oscillator

R : equivalent noise resistance of tuning diode

K_o : oscillator voltage gain

$$L\{f_m\} = f(Q_{load}, P_{s,av})$$

Design Parameters:

Q and signal power level

RF/Microwave Circuit Design for Wireless Application by U.L. Rohde and D.P. Newkirk, pp. 736 – 737.

Expected Phase Noise At 4.6 GHz

- ❑ *Measured* HBAR-based Oscillator's Phase Noise: -102dBc/Hz @ 10kHz offset
 - Center frequency (f_o): 3.68 GHz
 - HBAR's Q (Q_{load}): 19,000
 - Power consumption ($P_{s,av}$): 3.2 mW
- ❑ *Expected* HBAR-based Oscillator's Phase Noise: -95dBc/Hz @ 10kHz offset
 - Center frequency (f_o): 4.6 GHz
 - HBAR's Q (Q_{load}): 11,000 (based on the measured fQ product)
 - Power consumption ($P_{s,av}$): 3.2 mW

$$L\{f_m\} = 10 \log \left[\left\{ 1 + \frac{f_o^2}{(2f_m Q_{load})^2} \right\} \left\{ 1 + \frac{f_c}{f_m} \right\} \frac{Fk_B T}{2P_{s,av}} + \frac{2k_B T R K_o^2}{f_m^2} \right]$$

- ❑ *Hittite's* HMC429LP4's Phase Noise: -85dBc/Hz @ 10kHz offset
 - Center frequency (f_o): 4.45 – 5.0 GHz
 - Power consumption ($P_{s,av}$): 90 mW
- ❑ HBAR oscillator reduces the power consumption 30 times, yet still improves the phase noise by 10dBc/Hz, compared to a commercial VCO.

Expected Phase Noise At 9.19 GHz

- ❑ *Expected* HBAR-based Oscillator's Phase Noise: -79dBc/Hz @ 10kHz offset
 - Center frequency (f_o): 9.19 GHz
 - HBAR's Q (Q_{load}): 4,680 (based on the measured fQ product)
 - Power consumption ($P_{s,av}$): 3.2 mW
 - Noise factor F : about two times larger than that at 3.68 GHz

$$L\{f_m\} = 10 \log \left[\left\{ 1 + \frac{f_o^2}{(2f_m Q_{load})^2} \right\} \left\{ 1 + \frac{f_c}{f_m} \right\} \frac{F k_B T}{2P_{s,av}} + \frac{2k_B TRK_o^2}{f_m^2} \right]$$

Resonant Mass Sensors

- ❑ Output in frequency, monitored by electrical readout
- ❑ Inherent noise immunity, easy interface with digital systems
- ❑ Excellent minimum detectable mass, high sensitivity.

❑ Actuation:

- Optical
- Electrostatic
- Magnetic
- Piezoelectric



❑ Sensing:

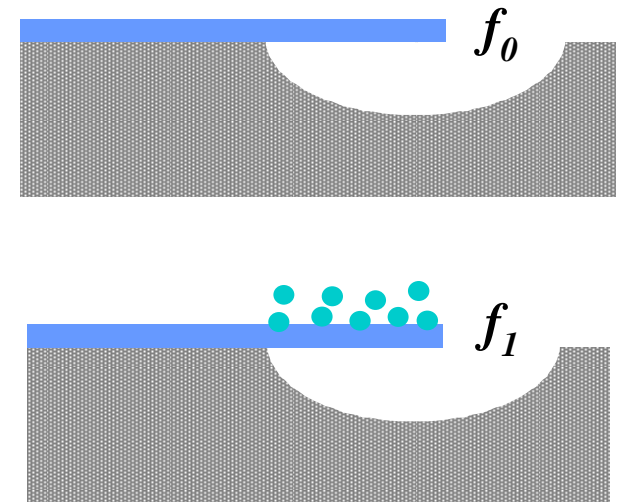
- Optical
- Capacitive
- Piezoresistive
- Piezoelectric



➤ Self actuation and sensing (with piezoelectric ZnO or AlN)

➤ Film bulk acoustic resonator (FBAR)

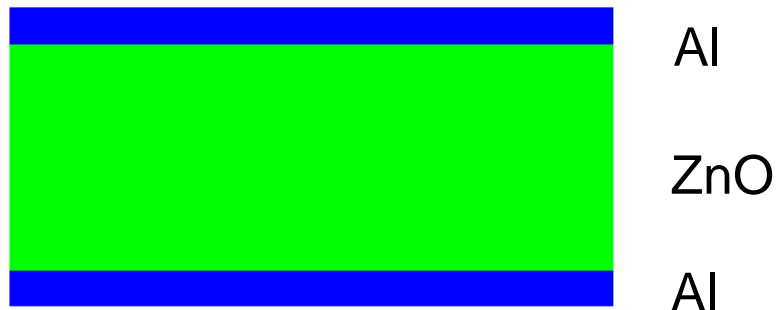
➤ More than 100 million FBARs per year produced in 6" CMOS fabs



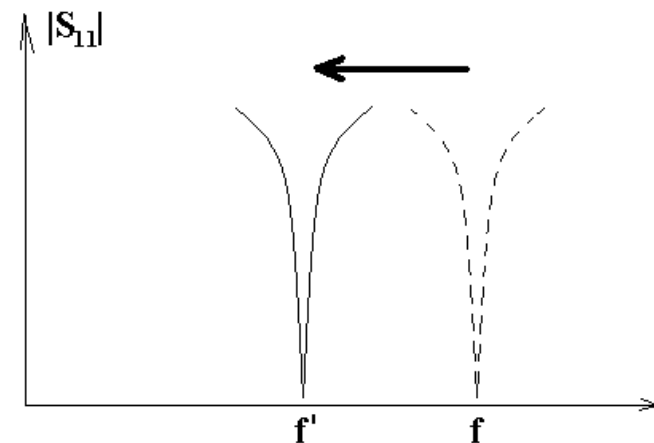
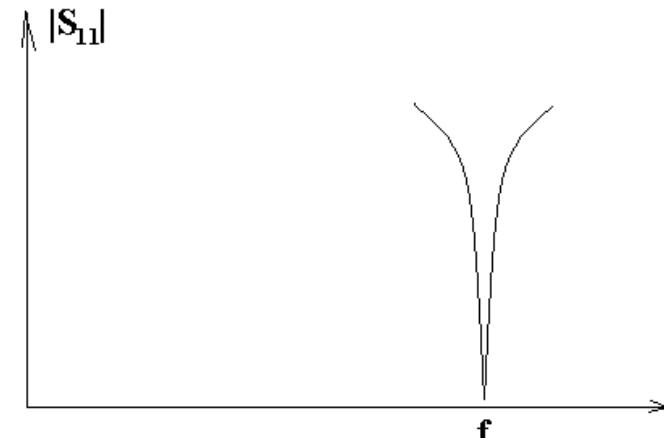
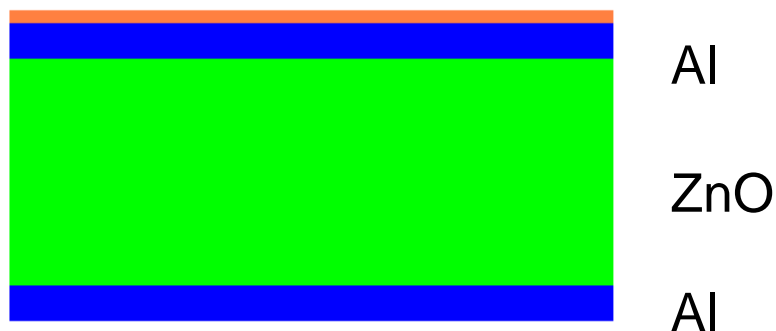
FBAR as a Mass Sensor

❖ FBAR consists of a deposited piezoelectric film, two metal electrodes and a supporting diaphragm (optional).

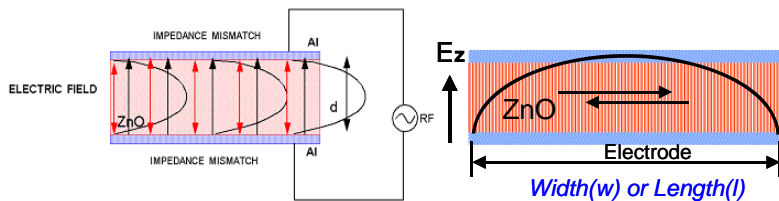
- its resonant frequency of ~GHz is determined by the thickness of its layers
- the resonant frequency decreases with any mass added to its surface.



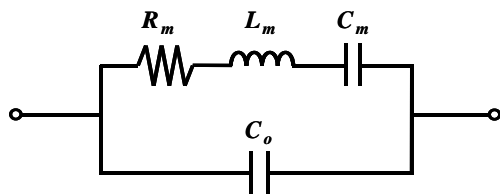
added mass



MEMS Resonator Characteristics (Piezoelectric vs. Electrostatic)



Piezoelectric



□ Electromechanical coupling coefficient

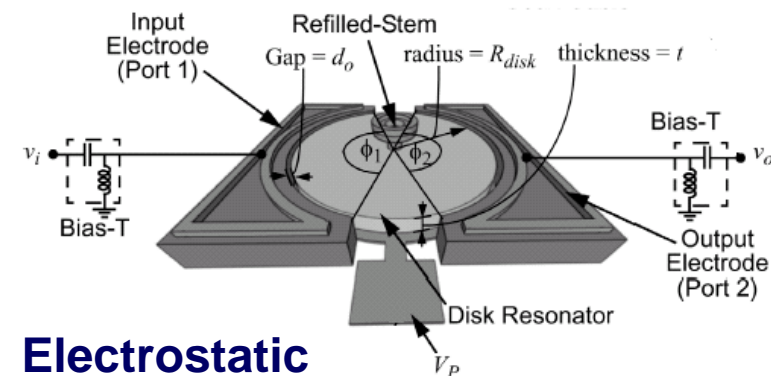
$$k_t^2 = \frac{e_{33}^2}{e_{33}^2 + c_{33}^E \cdot \epsilon_{33}^S}$$

Material dependent,
and more than **1%**

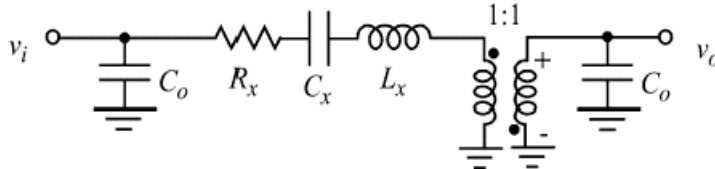
□ Input impedance
(motional resistance R_m)

$$R_m \propto \frac{1}{f_r \cdot Q}, \frac{1}{k_t^2}, d \text{ or } w, \frac{1}{A_{\text{electrode}}}$$

Easily matched to **50Ω**



Electrostatic



$$\eta \propto V_{DC}, \kappa, V_a, \frac{1}{f_r}, \frac{1}{d_0^2}, t$$

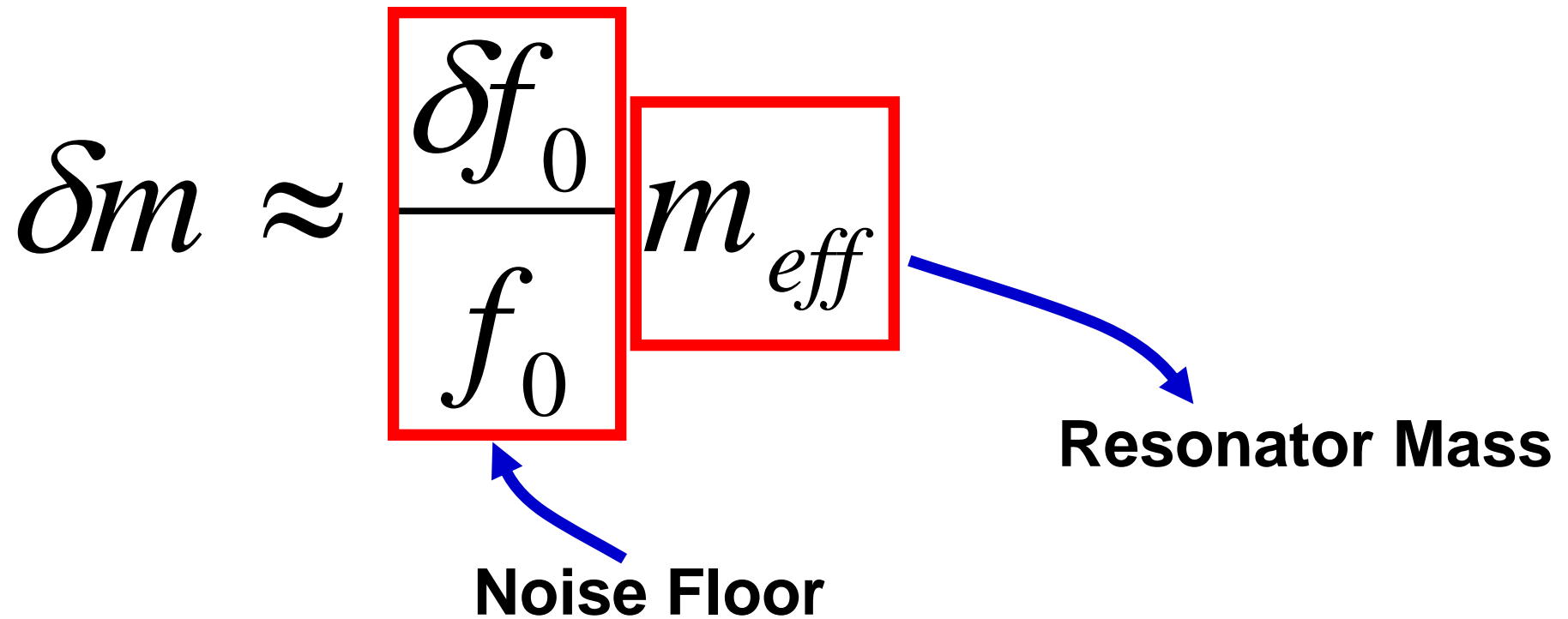
Typically less than
0.001%

$$R_x \propto \frac{1}{f_r \cdot Q}, m_{re}, \frac{1}{\eta^2}$$

Typically more than
50 kΩ

Minimum Detectable Mass (MDM)

$$\delta m \approx \frac{\delta f_0}{f_0} m_{eff}$$



- ❑ Minimum detectable mass (MDM) is determined by
 - resonator frequency fluctuation (thermo-mechanical noise) ← **Q factor**
 - resonator mass
 - noise of detection circuit

❑ Nano-scale resonator has low mass, but also has low Q in air

Mass Sensitivity in cm^2/g

❖ Mass sensitivity defined as resonant frequency change ($\Delta f/f$) per added mass ($\Delta m'$ in g/cm^2) is

$$\begin{aligned}
 S_m &= \lim_{\Delta m' \rightarrow 0} \left(\frac{\Delta f}{f} \right) \left(\frac{1}{\Delta m'} \right) \\
 &= -\frac{1}{\rho_0 d} \quad \text{or} \quad -\frac{1}{\rho_0 w} \\
 &= -726 \text{ cm}^2/\text{g} \quad \text{for 1.4 GHz FBAR Mass Sensor} \\
 &= -44 \text{ cm}^2/\text{g} \quad \text{for 60 MHz LEM Mass Sensor} \\
 &= -14 \text{ cm}^2/\text{g} \quad \text{for 6 MHz Quartz Crystal Microbalance (QCM)}
 \end{aligned}$$

❖ This sensitivity in cm^2/g is to be used for mass sensors detecting mass concentration (e.g., g/cc) in sensing environment.

❖ For detecting absolute mass quantity (e.g., g) brought to mass sensor, the sensitivity in g/Hz is a better barometer for intrinsic sensing capability.

Mass Sensitivity in g/Hz

$$S_m = \frac{\delta m}{\delta f} = \frac{m_{eff}}{f_0}$$

The smaller, the better.

□ LEM piezoelectric resonant sensor

$$S_m = \frac{\delta m}{\delta f} \approx 2 \frac{\rho}{V_a} w^2 l d$$

l : length of resonator
 w : width of resonator
 d : thickness of resonator

□ FBAR mass sensor

$$S_m = \frac{\delta m}{\delta f} \approx 2 \frac{\rho}{V_a} w l d^2$$

ρ : density
 V_a : acoustic velocity

□ LEM and FBAR sensors have comparable mass sensitivity with NEMS sensor when the lateral dimensions (e.g., w and l) are reduced.

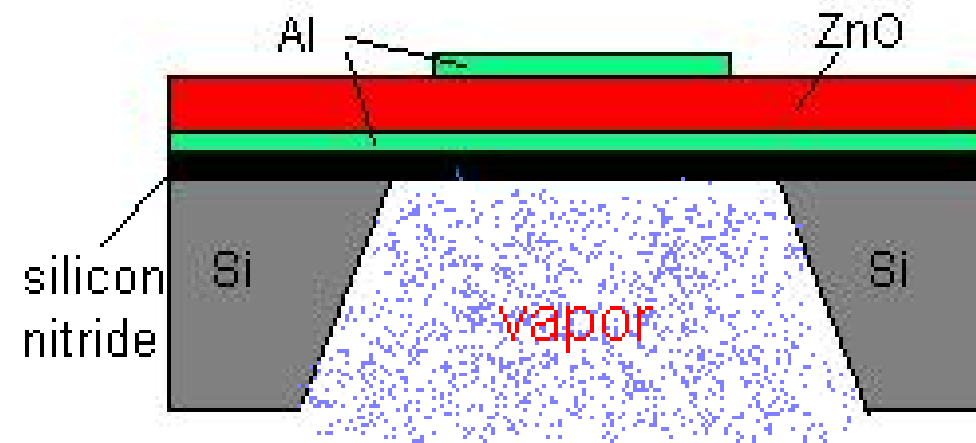
□ NEMS cantilever mass sensor

$$S_m = \frac{\delta m}{\delta f} \approx \pi \frac{\rho}{V_a} l^3 w$$

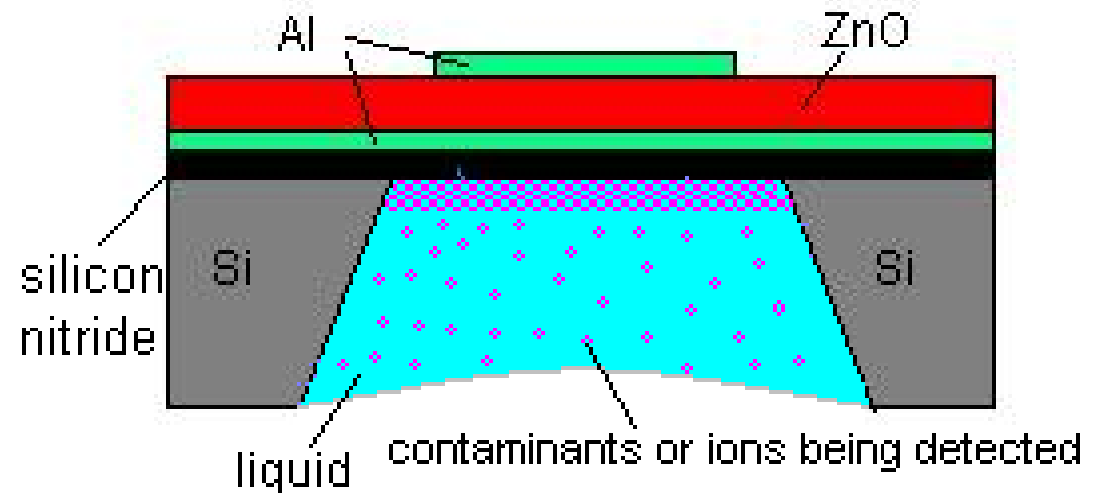
l : length of cantilever
 w : width of cantilever

S_m of $\sim 10^{-18}$ g/Hz is obtained with a NEMS sensor having $l = 2\mu\text{m}$ and $w = 2\mu\text{m}$.

FBAR Mass Sensor



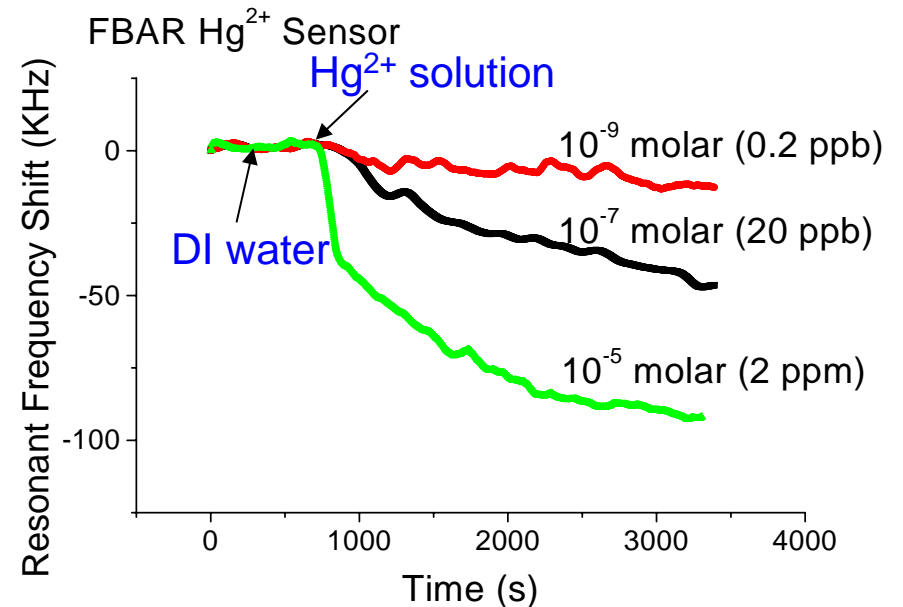
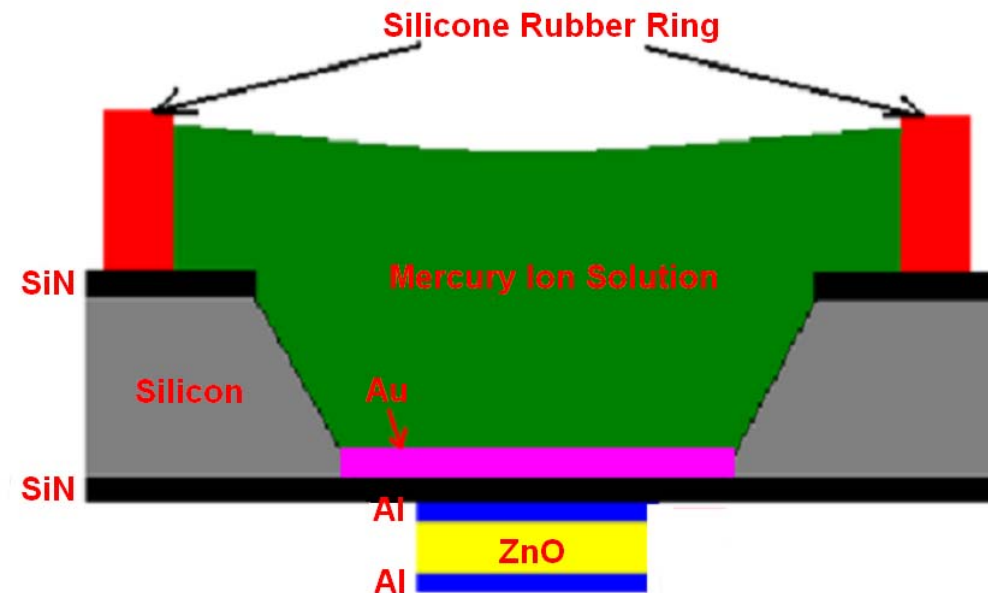
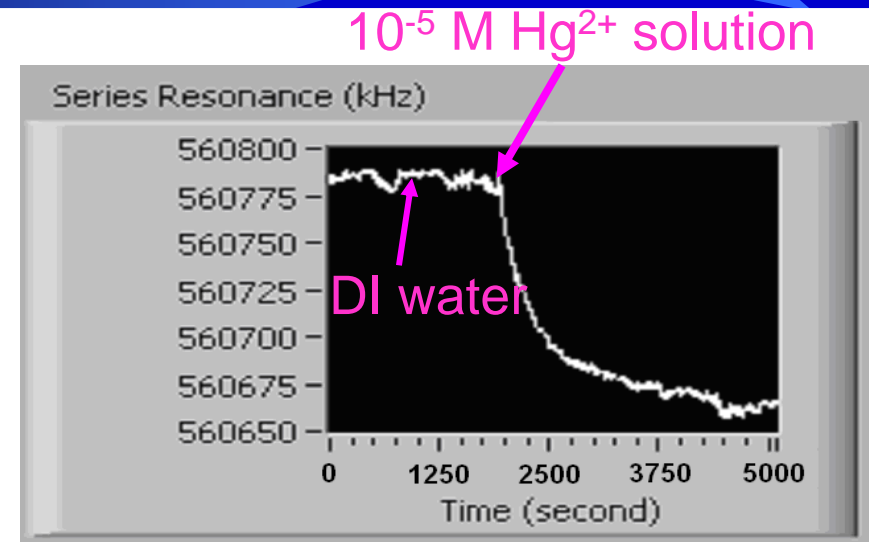
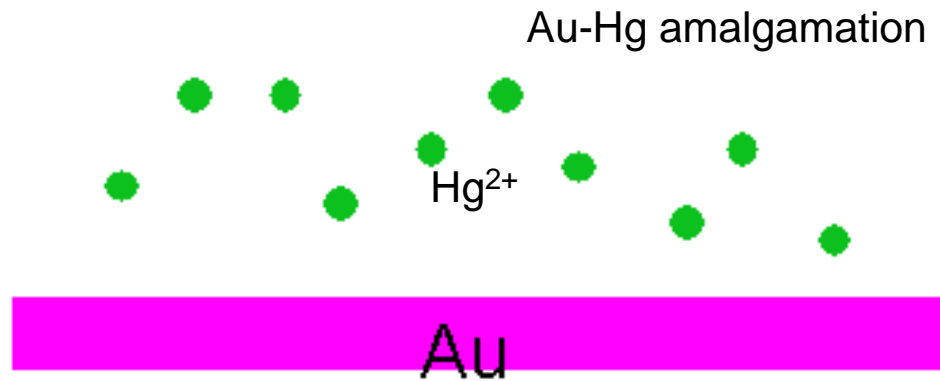
Vapor Mass Sensing



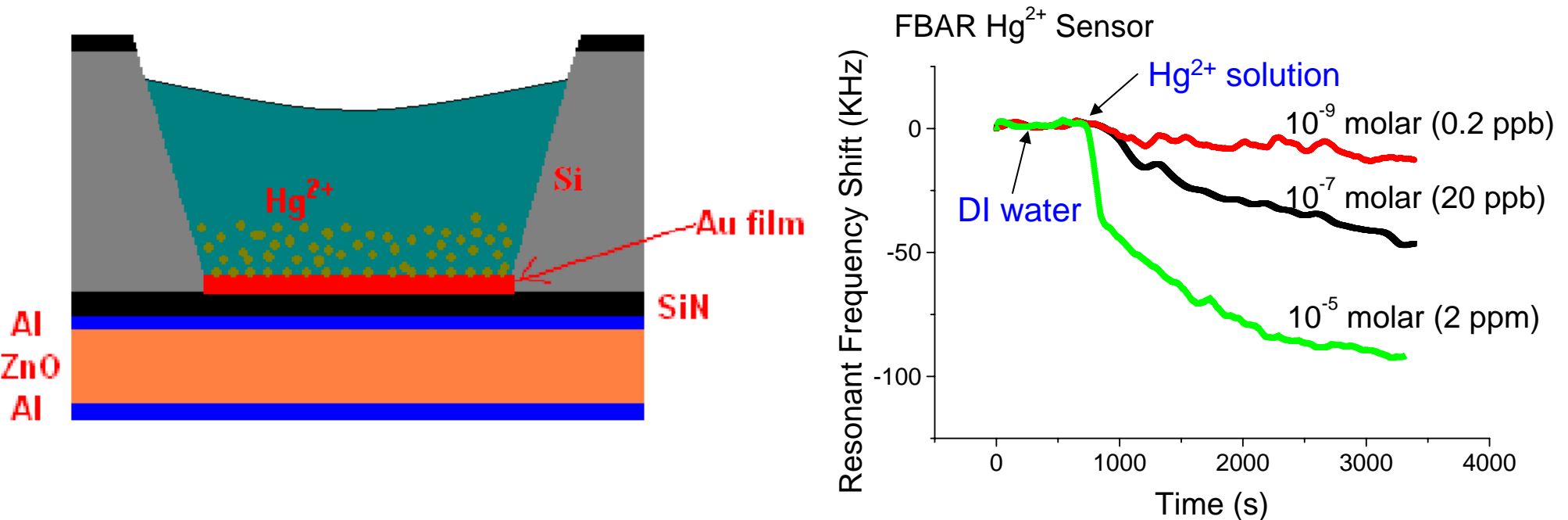
Mass Sensing in Liquid

- ❑ Easy packaging, array formation and impedance matching to 50Ω.
- ❑ Small size (100 μm × 100 μm × 2 μm)
- ❑ Operational in air and water.
- ❑ High mass sensitivity.
 - 10⁻¹⁸ g/Hz with small FBAR (10 μm × 10 μm × 2 μm).

Measured FBAR Response in Hg^{2+} Solution



Measured Mercury Ion Sensing by FBAR



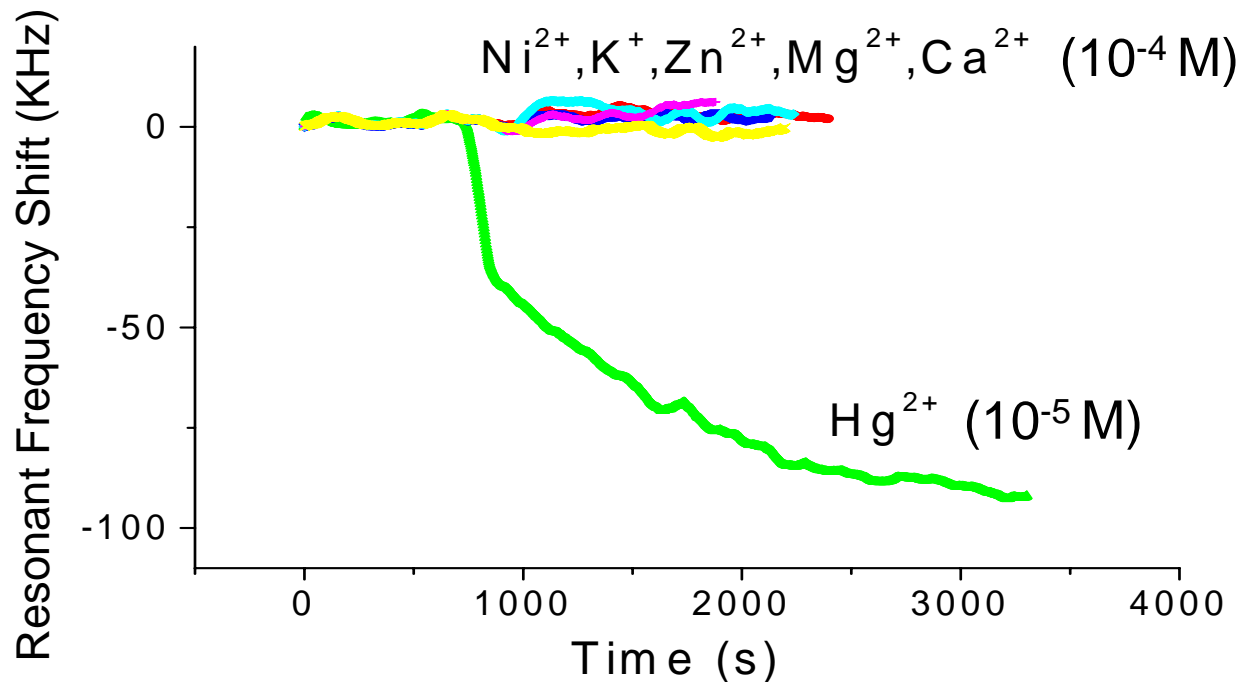
□ Detection limit: $\sim 10^{-9}$ M Hg²⁺ (0.2 ppb)

➤ According to the Environmental Protection Agency (EPA), drinking water should have Hg²⁺ concentration no higher than 2 ppb.

□ The sensor can be re-usable, since

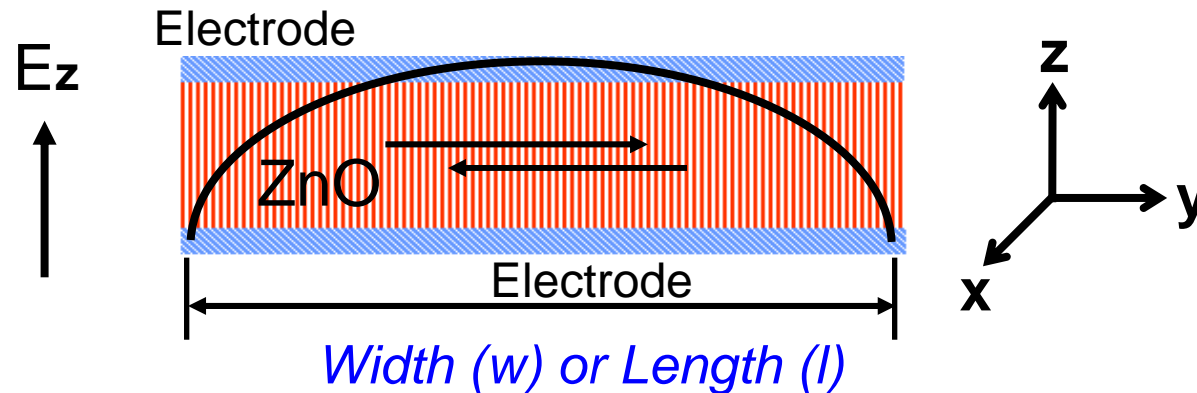
➤ the mercury ion can be released from the gold layer by brief heating or by 24 hour incubation at room temperature in a mercury-free atmosphere [McNerny J J, Buseck P R and Hanson R C 1972 Science **178**, 611].

Selectivity of the FBAR Mercury Sensor



- ❑ The selectivity of the Au-coated FBAR sensor for Hg^{2+} over other cations such as K^{+} , Ca^{2+} , Mg^{2+} , Zn^{2+} , Ni^{2+} is measured to be extremely good.
- ❑ None of the cations (all with a concentration of 10^{-4} M) can produce any significant frequency shift, while the FBAR resonant frequency changes around 90 kHz for $10^{-5} \text{ M Hg}^{2+}$

Lateral Extensional Mode (LEM) Piezoelectric Resonator



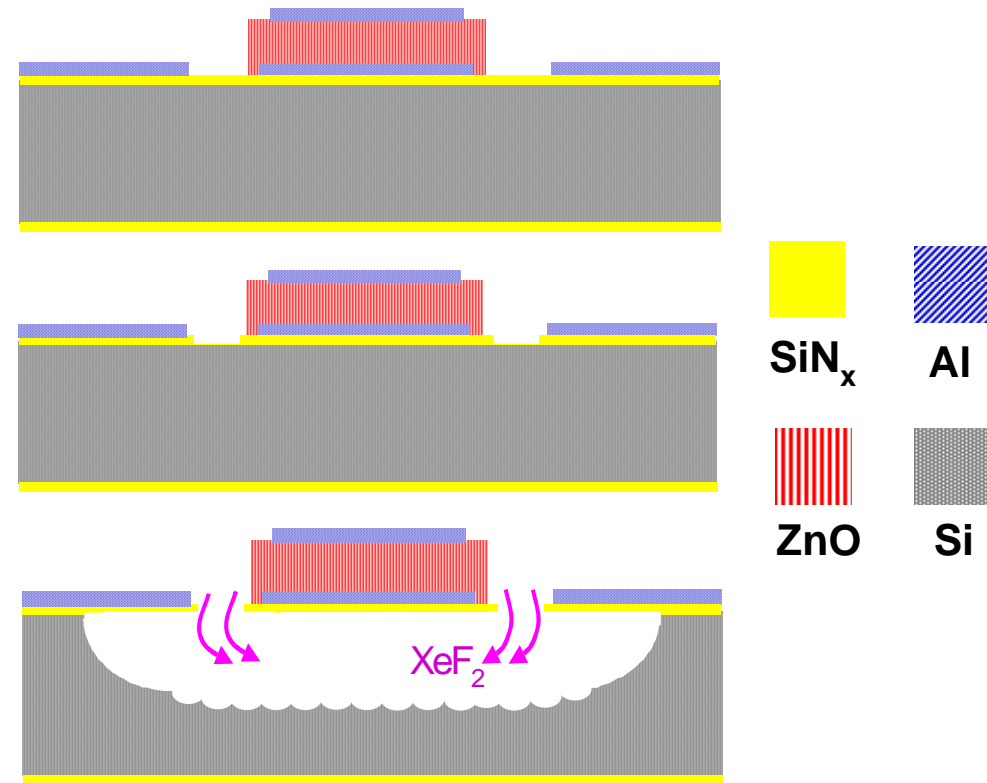
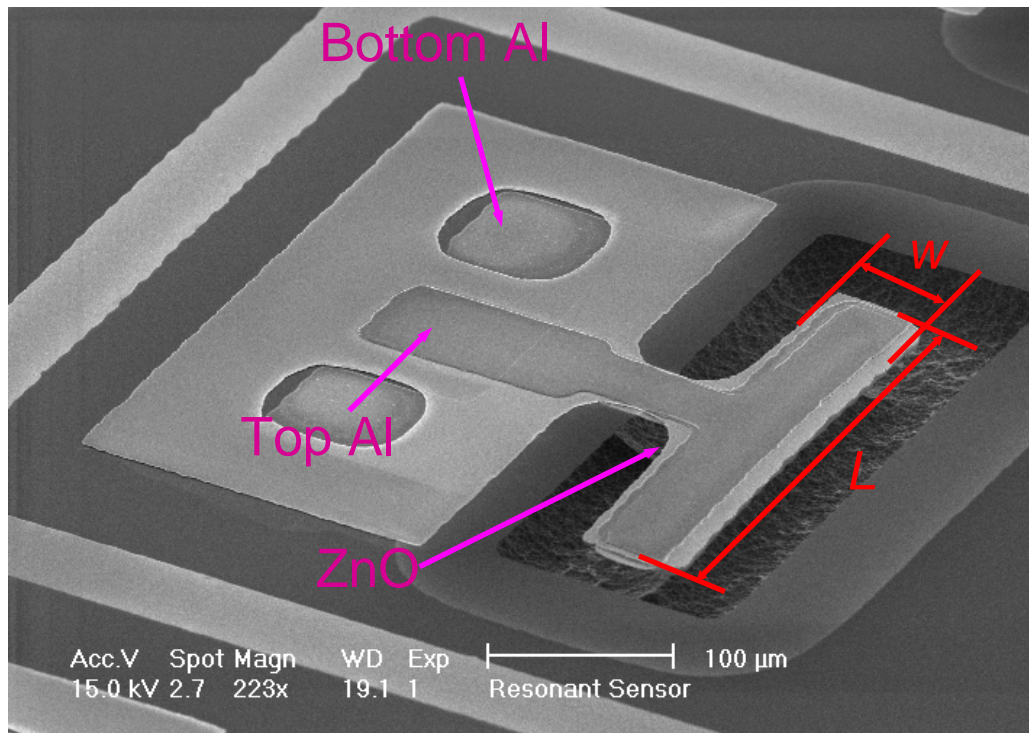
$$\begin{bmatrix} 0 & 0 & e_{31} \\ 0 & 0 & e_{31} \\ 0 & 0 & e_{33} \\ 0 & e_{15} & 0 \\ e_{15} & 0 & 0 \\ 0 & 0 & 0 \end{bmatrix} \begin{bmatrix} E_x = 0 \\ E_y = 0 \\ E_z \neq 0 \end{bmatrix} = \begin{bmatrix} T_x \neq 0 \\ T_y \neq 0 \\ T_z \neq 0 \\ T_{xy} = 0 \\ T_{yz} = 0 \\ T_{xz} = 0 \end{bmatrix}$$

□ Acoustic waves generated by **none-zero in-plane stress (T_x or T_y)**.

□ Resonant characteristics (e.g., $f=V/2w, Z_{in}$) are determined by the width and length.

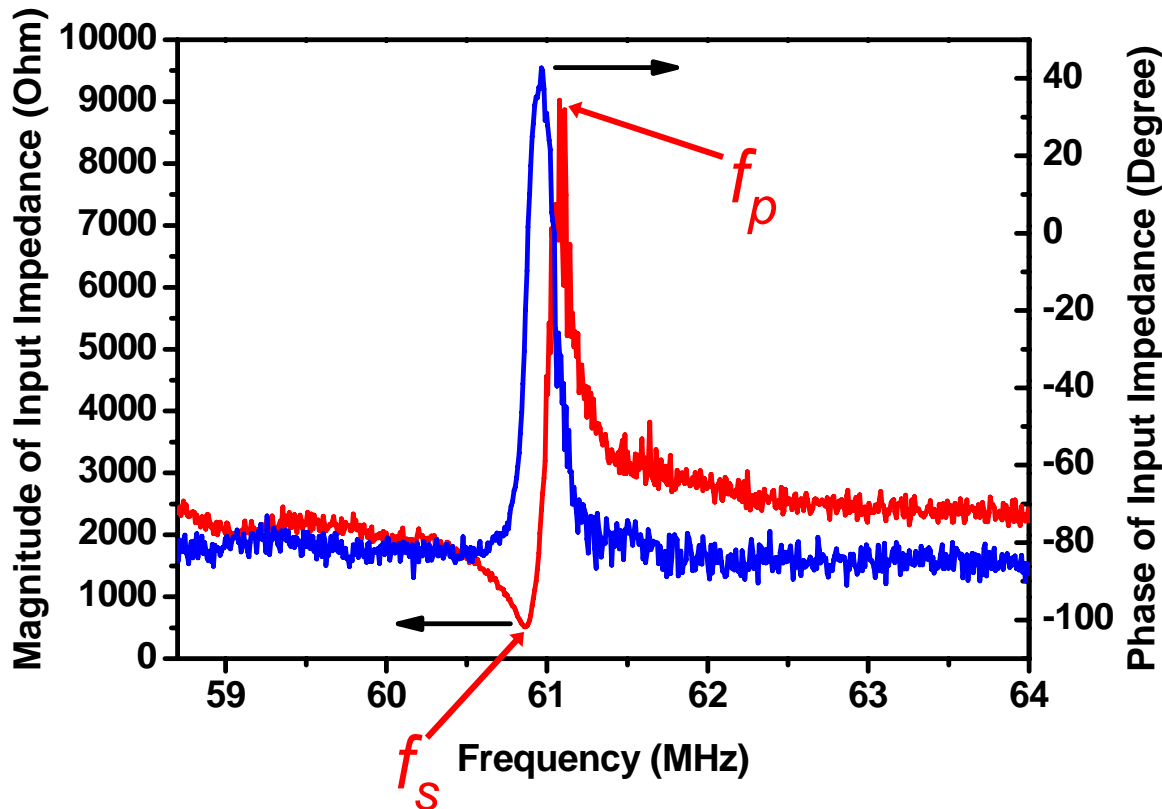
$$k_t^2 = \frac{K^2}{1+K^2} \quad V_a = \sqrt{\frac{C_{11}^E}{\rho}(1+K^2)} \quad K^2 = \frac{e_{13}^2}{c_{11}^E \cdot \epsilon_{33}^S} \quad k_t^2 \sim 1.7\% \quad V_a \sim 6100 \text{ m/s}$$

Fabrication of LEM Piezoelectric Resonator



- ☐ XeF₂ dry release with silicon as a sacrificial layer
 - CMOS compatible.
- ☐ Resonant frequency is photolithographically definable.
- ☐ Impedance could be decreased by increasing the length (L).

Measured Characteristics of LEM Piezoelectric Resonator

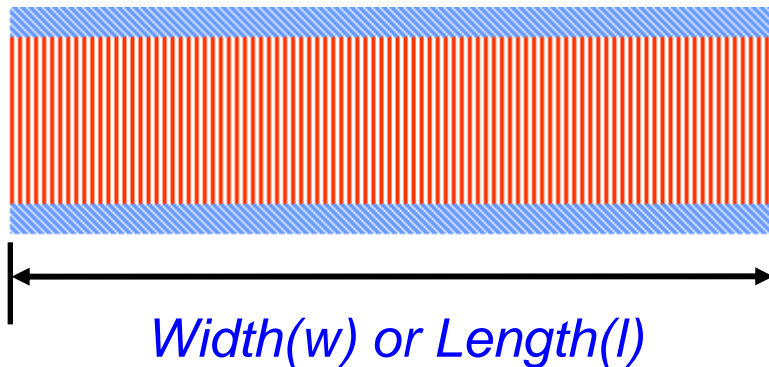


$$k_t^2 \approx \frac{\pi^2 (f_p - f_s)}{4 f_s} \approx 1.1\%$$

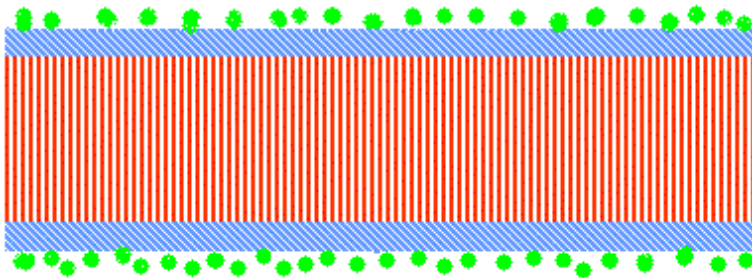
$$Q = \frac{f}{2} \frac{d\phi}{df} \approx 1,406 \text{ in air}$$

- ❑ Relatively high electro-mechanical coupling coefficient and Q
- ❑ Q is mainly determined by internal material property
 - Q of flexurally vibrating resonator is determined by viscous damping of air
- ❑ About 500 Ω impedance at f_s (≈ 61 MHz).
 - can be decreased by increasing the length (L).

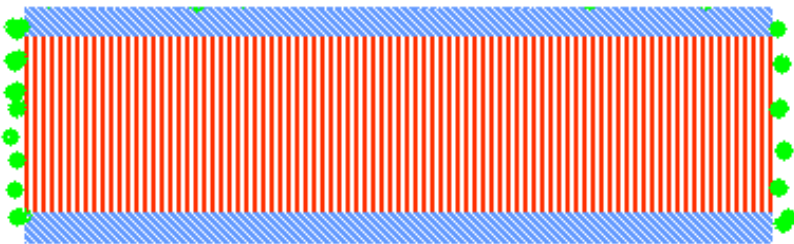
Resonant Frequency Shift Due to Mass Loading



❑ Resonance frequency (f_0) is determined by lateral dimension (*width or length*), not thickness (d).

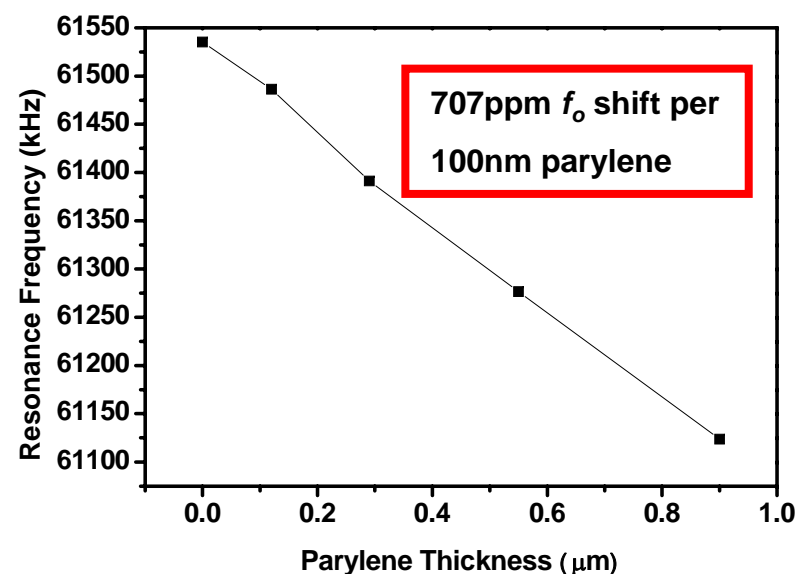
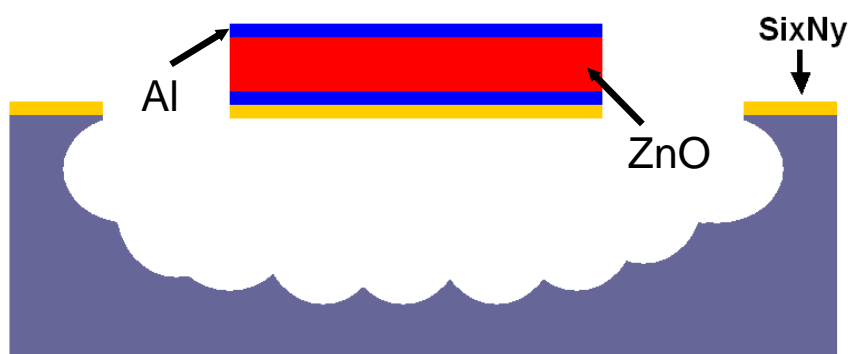
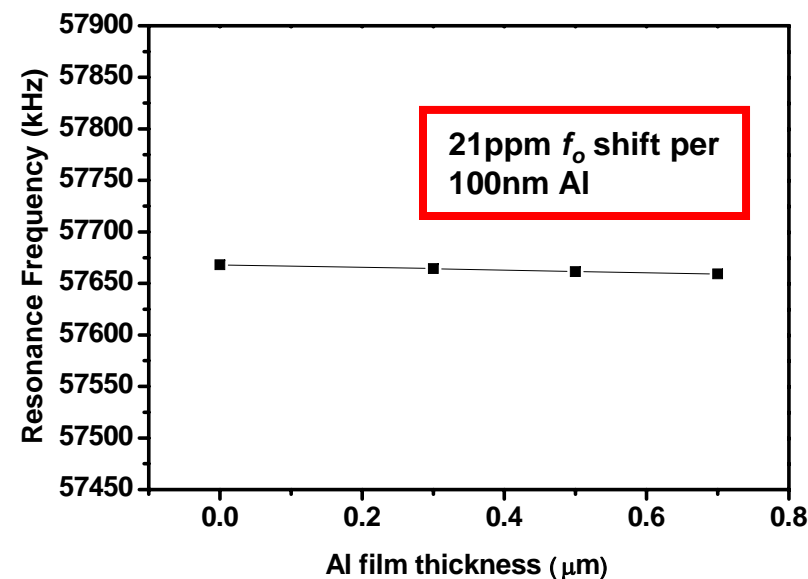
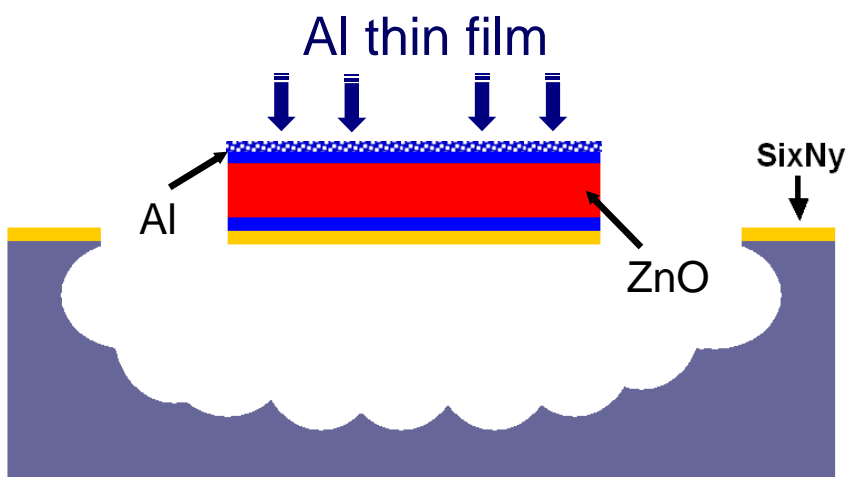


❑ The mass added on the top or bottom surface has little effect on the resonant frequency.



❑ The mass added on the sidewalls has pronounced effect on the resonant frequency.

Measured Resonant Frequency Shift Due to Mass Loading



Minimum Detectable Mass and Mass sensitivity

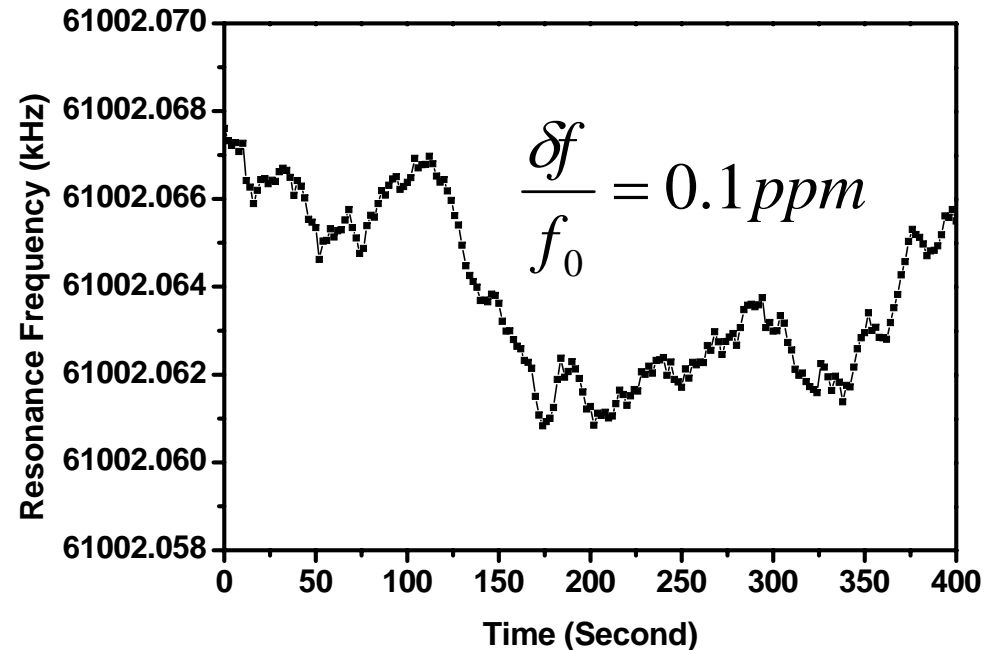
□ When mass change is much smaller than the mass of the resonator itself:

0.2μm Si_xN_y / 0.1μm Al / 0.6μm ZnO / 0.1μm Al

200μm×50 μm×1μm

$$\delta m \approx \frac{\delta f}{f_0} m_{\text{total}}$$

□ 0.1ppm noise floor corresponds to a minimum detectable mass change of $4.6 \times 10^{-15} \text{g}$ on the resonator's sidewall.



□ Mass sensitivity:

$$S_m = \lim_{\Delta m \rightarrow 0} \left(\frac{\Delta f}{f} \right) \left(\frac{1}{\Delta m} \right) = - \frac{1}{\rho_0 w} = 44.48 \text{ cm}^2/\text{g}$$

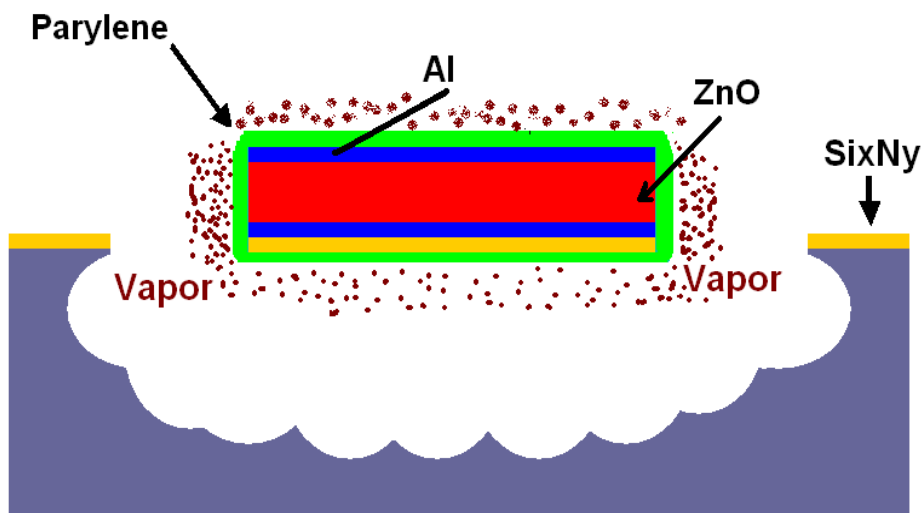
$$S'_m = \frac{\delta m}{\delta f} = \frac{m_{\text{eff}}}{f_0} \approx \frac{4.6 \times 10^{-8}}{60 \times 10^6} = 7.7 \times 10^{-16} \text{ g / Hz}$$

□ 0.1 ppm noise is dominated by resonator's sensitivity to temp. fluctuation

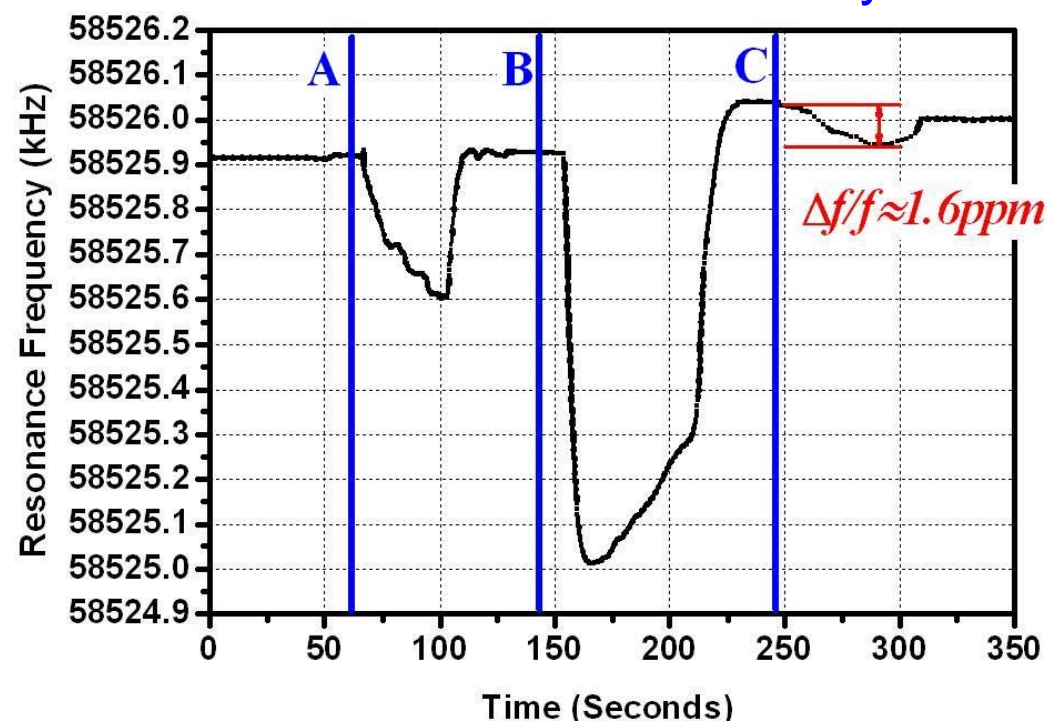
❖ Resonator TCF: ~-40 ppm/°C

$\rho_{\text{Al}} = 2.7 \text{ g/cm}^3$, $\rho_{\text{ZnO}} = 5.68 \text{ g/cm}^3$,
 $\rho_{\text{Si}_x\text{N}_y} = 2.85 \text{ g/cm}^3$, $\rho_{\text{polyene}} = 1.35 \text{ g/cm}^3$

Isopropanol Vapor Detection in Air



Measured Response of the LEM Resonator Coated with Parylene.



- The A, B and C are time points when different amounts of IPA are added.
- Minimum detectable frequency shift of ~1.6ppm corresponds to an added mass of about **73fg**.

$$\delta m \approx \frac{\delta f}{f_0} m_{total}$$

LEM Sensor in Comparison with Other Resonant Mass Sensors in Air

Resonant Mass Sensor		Device dimension $w \times l \times t$ (μm^3)	Operating frequency	Q factor		Minimum detectable mass (MDM) in air
				In air	in water	
LEM piezoelectric resonator		200×50×1	60MHz	1400	64	73 fg
FBAR		200×200×1.5	1.5GHz	~250	40	~1300 fg
Flexurally vibrating cantilever	laser detection	2×6×0.7	2.2MHz	25	N.A.	5.5 fg
	capacitive sensing	20×0.425×0.6	1.45MHz	70	N.A.	57 fg

□ LEM piezoelectric resonant sensor

- femtogram mass detection in air, at room temperature.
- portability, low power consumption.
- MDM is expected to be 1,000 times better by shrinking the size.
 - ❖ real-time detection of molecules without vacuum.

Microprobe with Resonant Mass Sensor

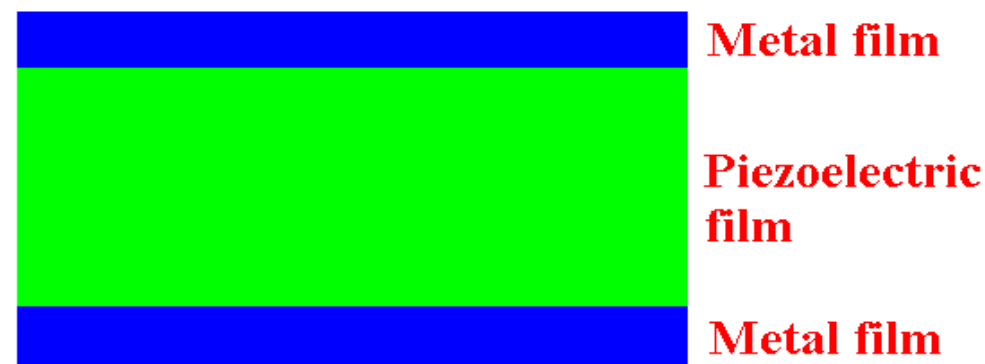


❖ FBAR mass sensor on probe tip

▶ to detect neuron firing by sensing ion concentration change instead of potential change

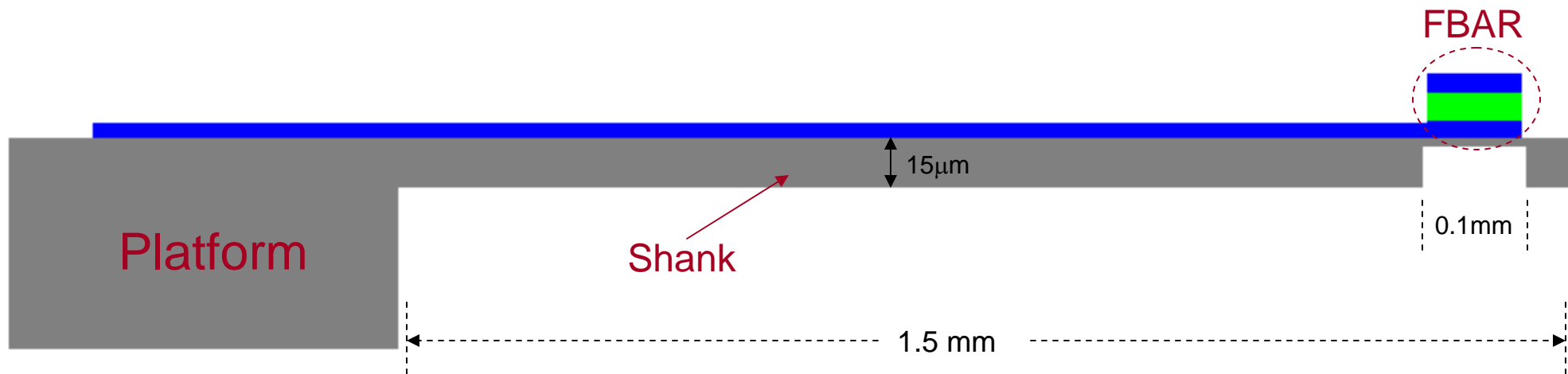
- for studying biophysics of neural signal propagation.

▶ to detect heavy metal ions, DNA hybridization, protein reaction, etc.



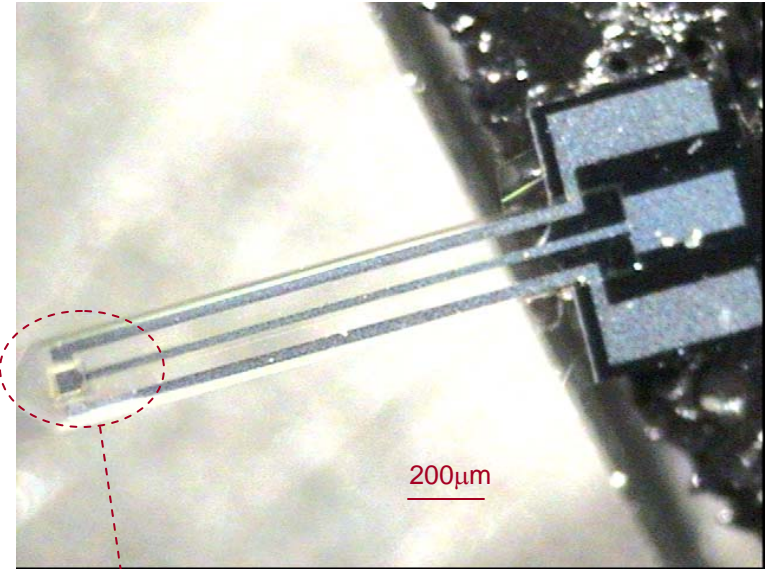
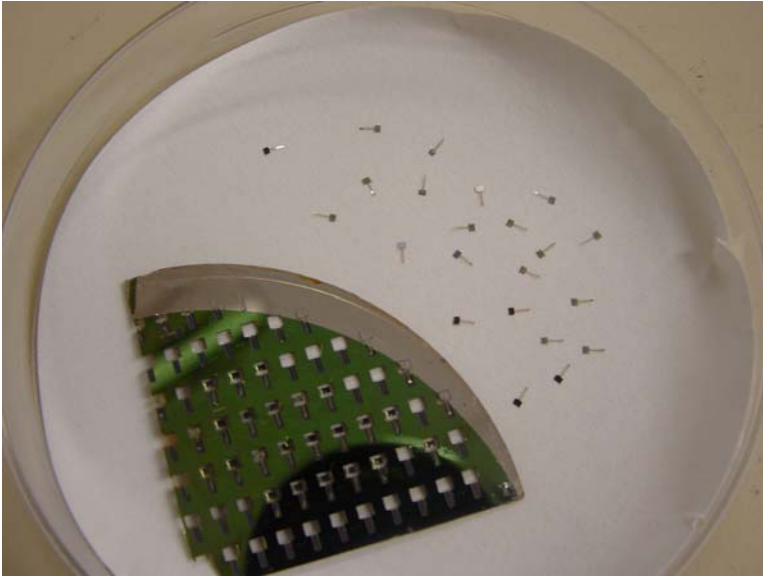
Film-Bulk-Acoustic-Resonator (FBAR)

FBAR on Micromachined Probe

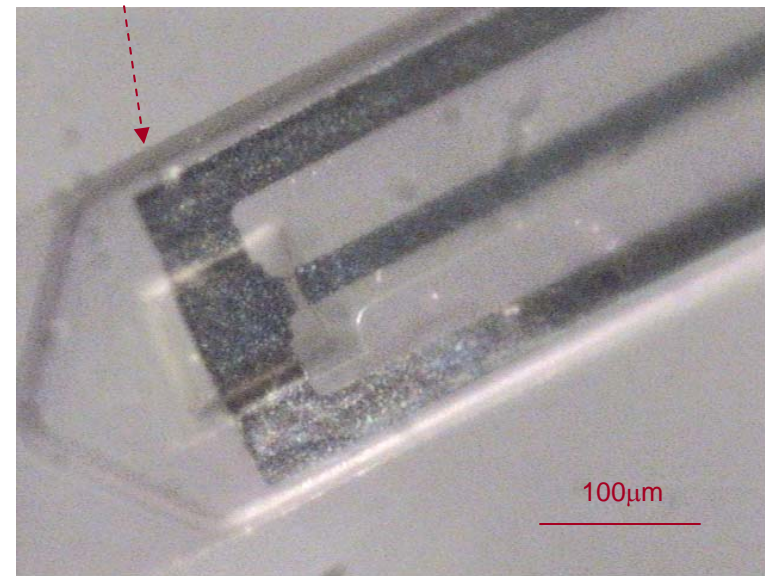


- ❖ FBAR's size minimized to be placed at probe tip.
- ❖ Support layer under FBAR must be thin for high Q.
- ❖ Long leading electrode from FBAR to platform requires shank with low RF loss
 - SU-8 for the shank
 - Much lower RF loss than silicon
 - Flexible and sturdy

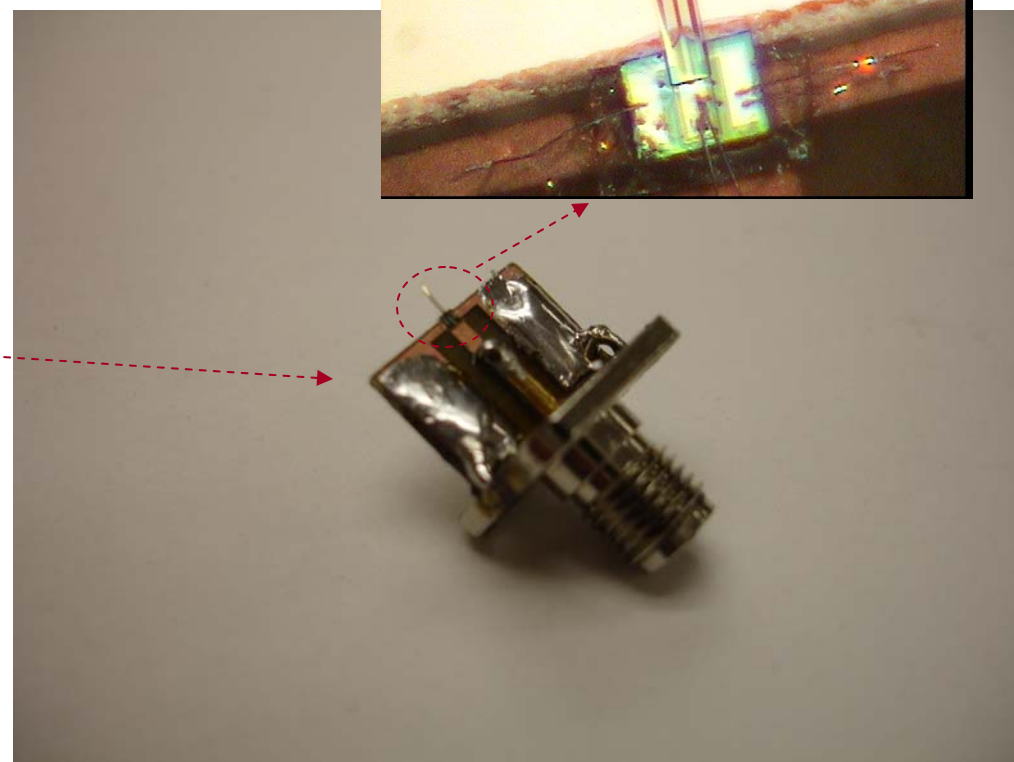
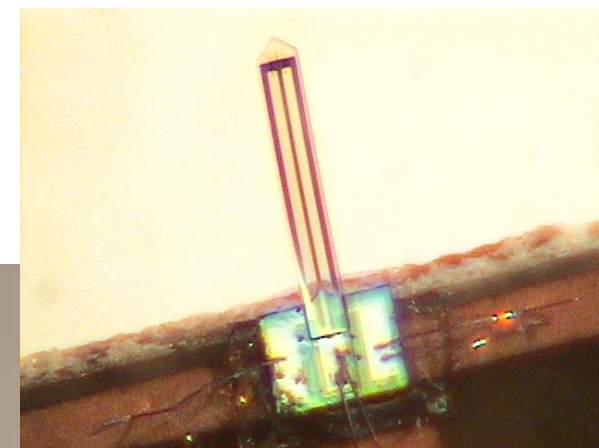
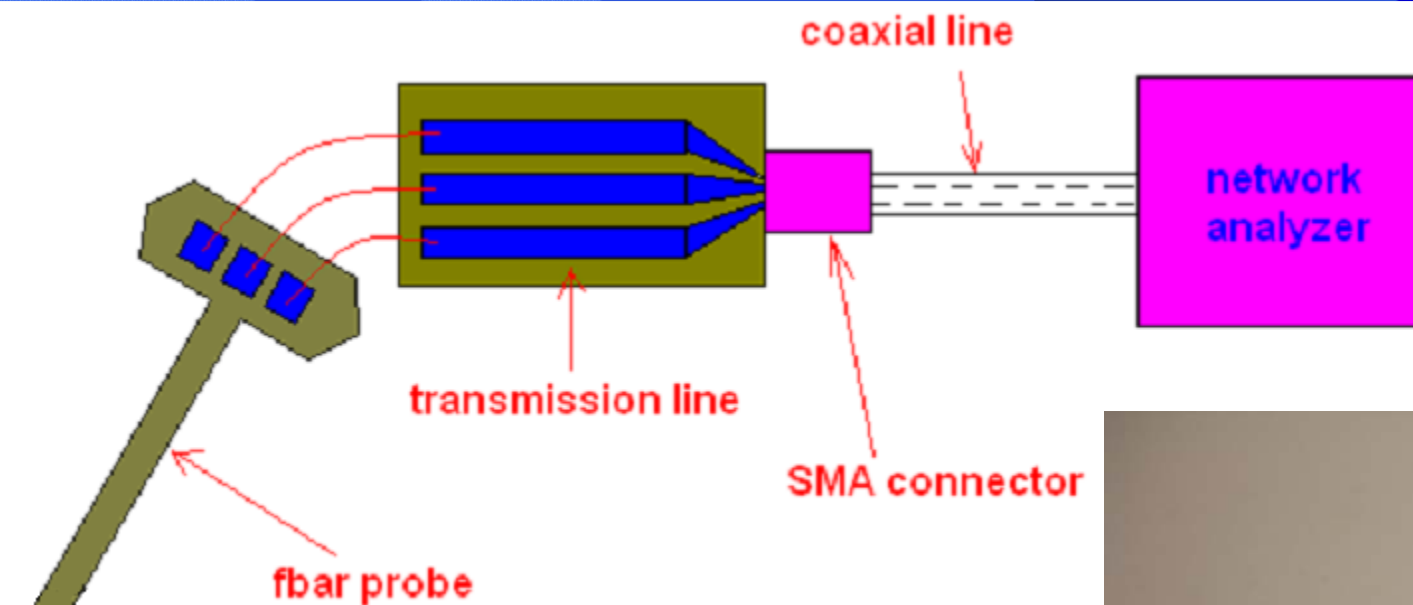
Pictures of Released SU-8 Probes



forced to bend by about 70°



SU-8 Probe Wire-bonded to Copper Transmission Line



Summary

- ❖ **3.68 GHz oscillator based on HBAR having a loaded Q of 19,000**
 - phase noise: -102dBc/Hz @10kHz offset
 - 3.2 mW power consumption.
 - Allan deviation: 1.5×10^{-9} @ 1 sec for a free-running oscillator.
- ❖ **Single-mode HBAR with Q of 7,300 at 3.13 GHz**
 - integrated with FBAR filter on a single chip $0.8 \times 0.4 \times 0.4 \text{ mm}^3$.
- ❖ **Temperature-compensated HBAR**
 - total frequency shift of 8.16ppm from 60 to 90°C.
- ❖ **1.4 GHz FBAR's mass sensitivity of 726 cm²/g**
 - minimum detectable mass density of 1 ng/cm² in air where the Q is 250.
- ❖ **60 MHz LEM resonator**
 - 4.6 fg minimum detectable mass
 - measured 73 fg isopropanol vapor detection
- ❖ **Attogram mass detection by scaling down the size to submicron scale.**
- ❖ **Hg²⁺ sensing by FBAR based sensor**
 - 0.2 ppb minimum detection with FBAR having Q of 400.
- ❖ **Micromachined SU-8 probe with an integrated FBAR sensor at its tip**